

# A Comparator-Based Switched-Capacitor Delta Sigma Modulator

by

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## **ABSTRACT**

Comparator-Based Switched-Capacitor (CBSC) is a relatively new topology that replaces op-amps in sampled-data systems with a comparator and a set of current mirrors. CBSC is expected to lower power consumption, and to avoid several delicate tradeoffs of op-amp circuits. In this paper, the original single-ended CBSC block is extended to a fully differential version. The differential CBSC is then applied to an industrial standard second order delta-sigma modulator originally based on op-amps. Due to the differences between CBSC and op-amp, a few architectural changes are necessary for the original modulator. Finally, the performance of transistor level simulation of this CBSC based modulator is evaluated.

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# Chapter 1

## Introduction

### 1.1 Motivation

Advancement in modern technology has led to an increasing number of digital applications. However, because we live in an analog world, we need to convert the analog signals into digital signals before we can process them. The building block that is being used to accomplish this task is called an Analog-to-Digital Converter (ADC). There are a few major ways to build an ADC. Each of them has its pros and cons [1] [2] [3]. As can be seen in Table 1-1,  $\Delta\Sigma$  ADCs have the advantage of offering the highest resolution of the various types.

However,  $\Delta\Sigma$  ADCs have several drawbacks as well. It has becoming more and more challenging to compensate op-amps for high gain-bandwidth in scaled technologies[4]. These ADCs also suffer an increase in power consumption (mainly from op-amp usage) in order to maintain conversion speed while the power supply is lowered [4]. In another words, op-amp has become the bottleneck of  $\Delta\Sigma$  ADCs in terms of meeting the power consumption and speed requirements. As a potential solution to this problem, Comparator-based switched-capacitor (CBSC) circuits are introduced in [4] to eliminate the usage of op-amps. This thesis discusses the design and performance of a 2<sup>nd</sup> order  $\Delta\Sigma$  modulator using CBSC circuits.

Table 1–1: Comparison of the four types of ADCs

Type	Advantages	Disadvantages
Parallel design (i.e. flash ADC)	Simple Fastest Can be non-linear	Large number of components: $2^n-1$ comparators
DAC-based design (i.e. successive approximation)	A single comparator can realize a high resolution ADC Buffered: last converted value can be read while the ADC is converting the current value	Slow: requires $2^{(n-1)}$ clock cycles
Pipeline ADCs	Fast Low power High resolution Small die size	Latency Need calibration Needs a non-trivial analog Anti-Aliasing filter
Integrator-based design (i.e. single-slope)	Buffered	Calibration drift leads to inaccuracy over time
Delta-sigma ( $\Delta\Sigma$ ) design	Very high resolution Widely applicable	Requires oversampling, which means higher than Nyquist rate clocks. Power consumption

\*n = number of bits used in ADC

## 1.2 Thesis Organization

Chapter 2 provides a brief introduction to CBSC technology. The basic principles and operation of CBSC circuits are introduced in this chapter. Chapter 3 introduces an op-amp based feed-forward  $2^{\text{nd}}$  order  $\Delta\Sigma$  modulator architecture. This architecture is the model of the CBSC  $2^{\text{nd}}$  order  $\Delta\Sigma$  modulator proposed in this thesis. Chapter 4 covers the design of a CBSC  $2^{\text{nd}}$  order  $\Delta\Sigma$  modulator. This chapter first discusses the architectural change to the op-amp based modulator. Then the details of each building block are presented along with changes made to the original CBSC technique. Chapter 5 shows the simulation results and comparison of the different versions of  $2^{\text{nd}}$  order  $\Delta\Sigma$  modulators: Matlab, op-amp based, CBSC based ideal component circuit, and CBSC based transistor level circuit. This chapter also provides a comparison of the power usage between an op-amp based  $\Delta\Sigma$  modulator and a CBSC  $\Delta\Sigma$  modulator. Chapter 6

discusses the advantages and the disadvantages of the CBSC  $\Delta\Sigma$  modulator. In the end, future work and ideas are suggested in Chapter 7.

# Chapter 2

## Intro to CBSC

### 2.1 CBSC Circuits vs Op-Amp Based Circuits

Fig. 2-1 and Fig. 2-2 from [4] both use the switched-capacitor architecture; however, in Fig. 2-2 the op-amp in Fig. 2-1 is replaced by a comparator. The main difference between the two building blocks is that the op-amp forces the virtual ground while the comparator detects the virtual ground. The output voltage plots show that they both have similar behavior, except that one settles exponentially while the other one settles linearly. It can also be mathematically proven that the comparator-based circuit works the same as the op-amp based circuit (see Appendix A.1 and A.2).

There are several advantages of the comparator-based switched-capacitor (CBSC) topology. First, just like the op-amp based switched capacitor circuits, the CBSC circuits use two-phase clocking, sampling phase and evaluation phase. The difference is that in a CBSC circuit all the current sources connected to the output nodes are off at the end of the evaluation phase, which is good for low-voltage applications [5]. Second, preliminary analyses indicate that detecting the virtual ground condition (CBSC circuits) is more energy efficient than forcing the virtual ground (op-amp based circuits)[6]. Also, the op-amp approach has a feedback path, which

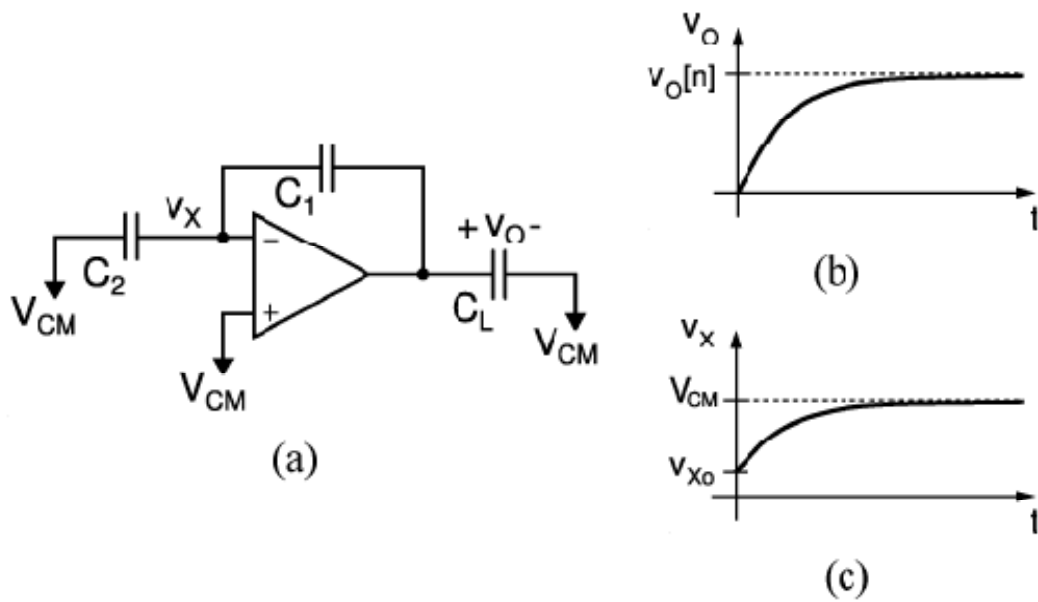


Figure 2-1: Op-amp based switched-capacitor gain stage transfer phase. (a) Switched-capacitor circuit. (b) The output voltage exponentially settles to the final values. (c) The summing node voltage exponentially settles to the virtual ground condition.[4]

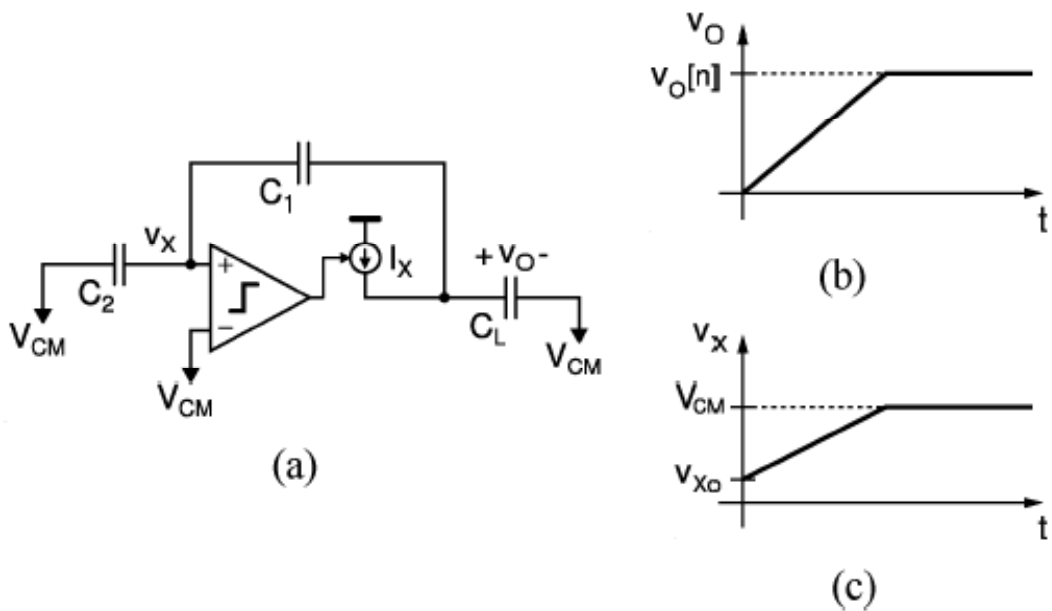


Figure 2-2: Comparator-based switched-capacitor gain stage charge transfer phase. (a) Switched-capacitor circuit with an idealized zero delay comparator. (b) The output voltage ramps to the final value. (c) The summing node voltage ramps to the virtual ground condition. [4]

needs to be stabilized. The techniques used to stabilize the amplifier require increased power consumption to maintain the same operational speed [4]. On the other hand, CBSC does not have a stability problem because it has an open-loop. Thus, CBSC doesn't consume as much power. Finally, the CBSC design methodology is expected to be applicable to a wide range of capacitively loaded switched-capacitor circuits and expected to be compatible with most known architectures [4]. However, successful implementation of CBSC  $\Delta\Sigma$  modulator with real test results is not demonstrated in literature yet.

## 2.2 CBSC Charge Transfer Phase

Even though a CBSC circuit behaves very similarly to an op-amp based circuit, it has a very unique charge transfer phase. Fig. 2-3, Fig. 2-4, and Fig. 2-5 from [4] shows the three charge transfer steps: preset phase (P), coarse charge transfer phase (E1), and fine charge transfer phase (E2).

During the preset phase (Fig. 2-3), node  $v_o$  is grounded,  $v_x$  brought below  $v_{cm}$  (see Appendix A.2 for calculation). During coarse charge transfer phase in Fig. 2-4, current source E1 provides current to the rest of the circuit until  $v_x$  equals to  $v_{cm}$ . As a result, it successfully integrates the current value (see Appendix A.2).

However, the charge transfer process is not so perfect in reality, because non-ideality exists in the circuit. One source of error comes from the comparator delay, which causes  $v_o$  to overshoot, as shown in Fig. 2-4, b).

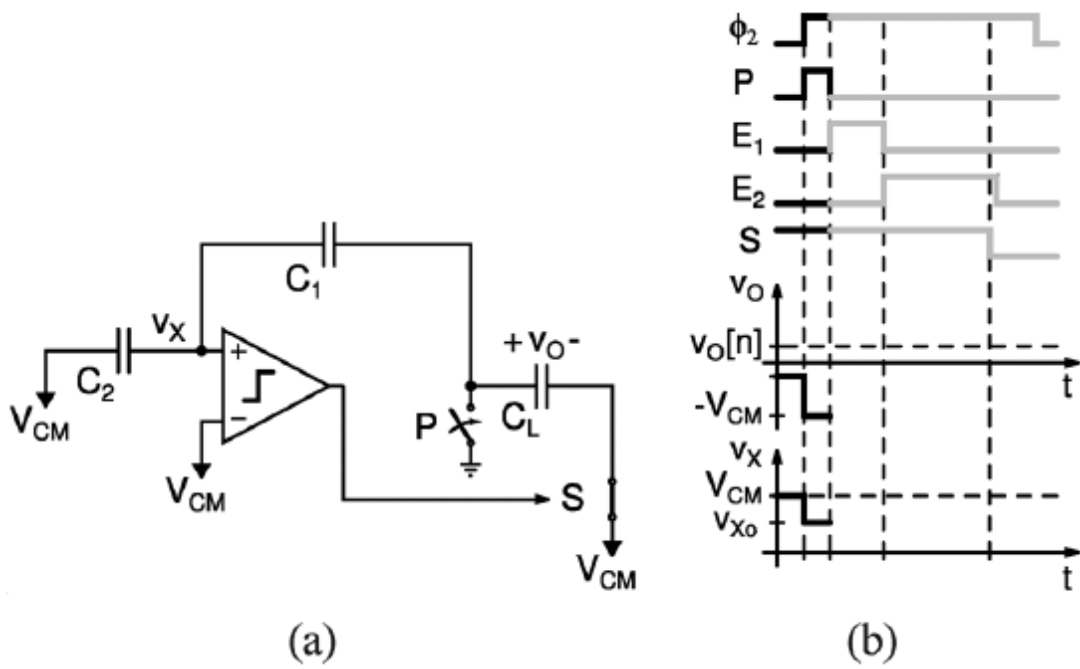


Figure 2-3: Preset phase (P). (a) Switch P Closes. (b)  $v_o$  grounded and  $v_x$  brought below  $V_{cm}$  [4]

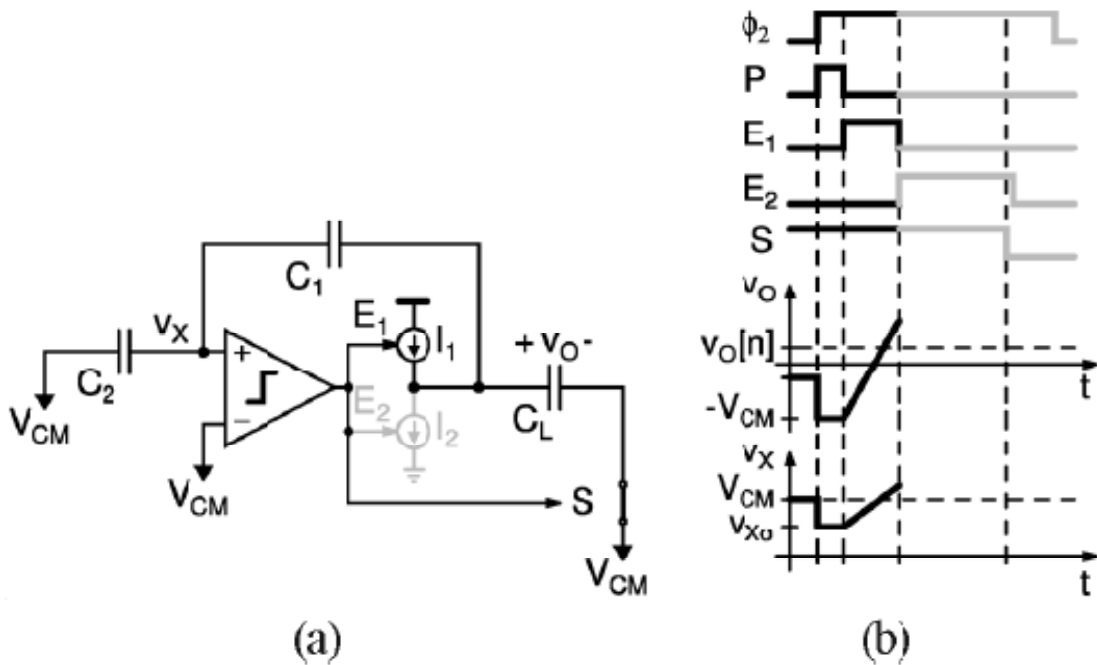


Figure 2-4: Coarse charge transfer phase ( $E_1$ ). (a) Current source  $I_1$  charges output. (b)  $v_o$  and  $v_x$  ramp and overshoot their ideal values.[4]

To overcome the overshoot caused by comparator delay, another current source E2 is added to correct this error. Instead of providing current, current source E2 sinks current causing current to reverse until the voltage drops below  $v_{cm}$ . Because the current of E2 is much smaller than current of E1, the overshoot will be much smaller than the original one. Thus, E2 acts as an overshoot correction phase, Fig. 2-5.

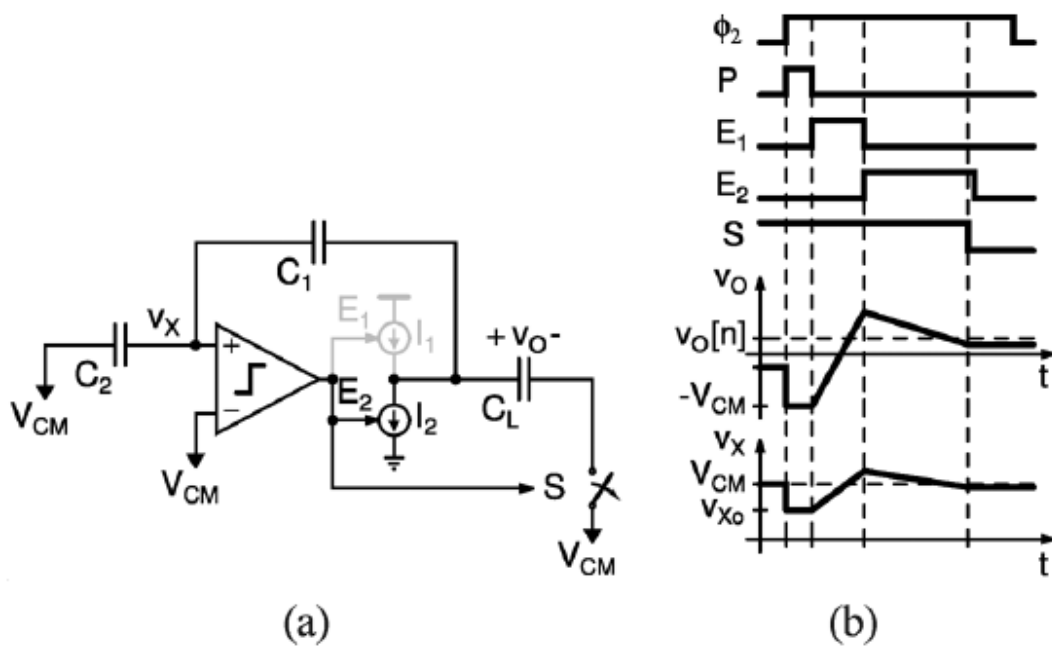


Figure 2-5: Fine charge transfer phase ( $E_2$ ). (a) Current source  $I_2$  discharges output. (b)  $v_o$  and  $v_x$  ramp to their final values. [4]

### 2.3 CBSC Application in Pipelined ADC

A common application of the CBSC circuit is in pipelined ADC design [4], Fig. 2-6. Here, the CBSC circuit is used to provide a constant gain of  $\frac{C_2}{C_1}$ , using the direct charge transfer (DCT) sampling method, Fig. 2-7.



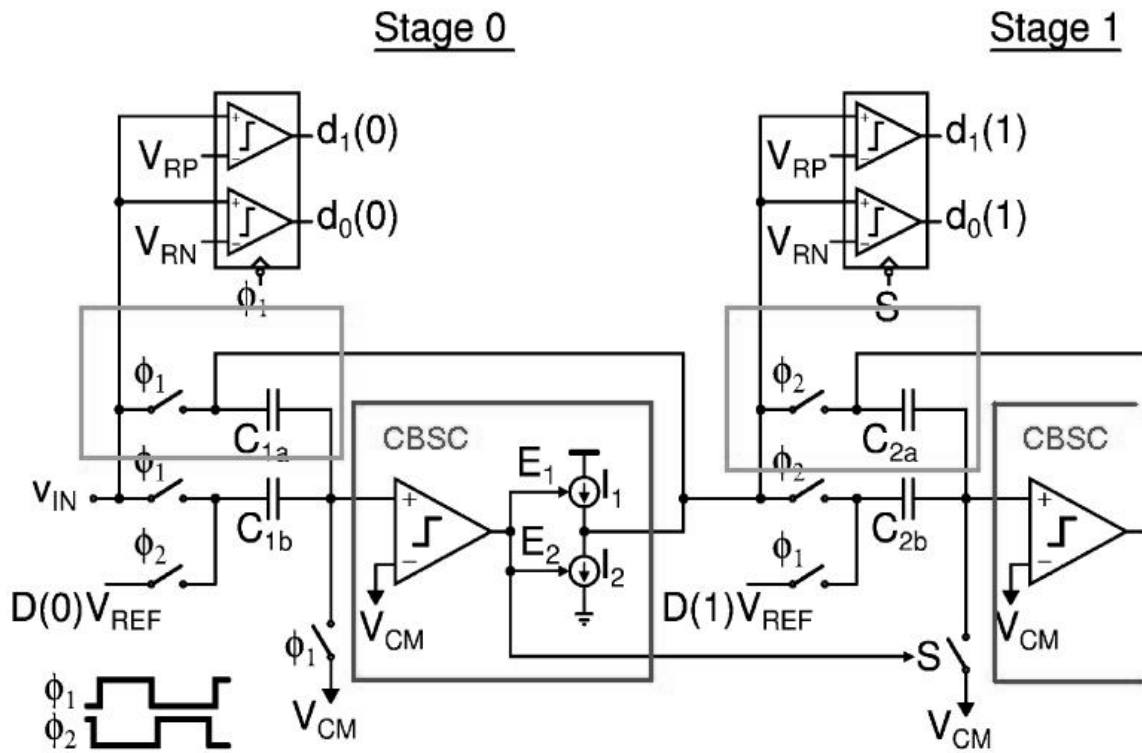


Figure 2–6: CBSC pipelined ADC design [4]

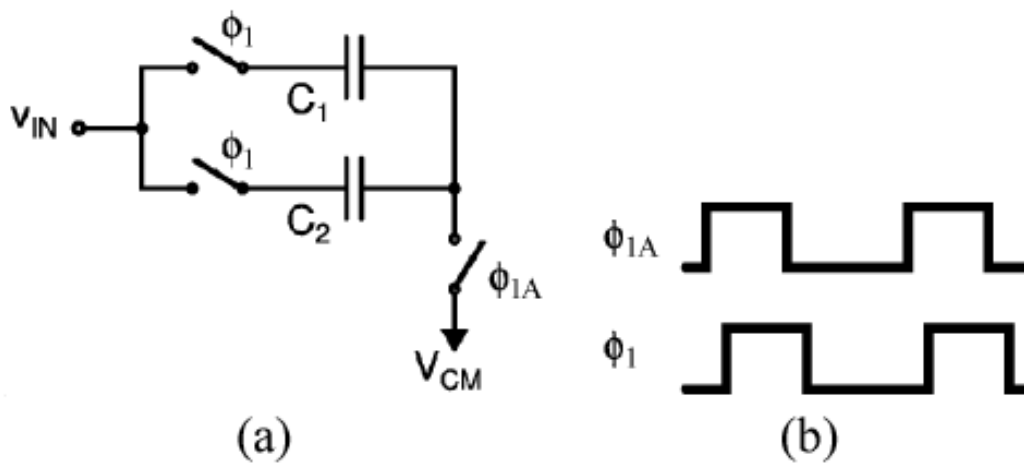


Figure 2–7: Sampling phase of pipelined ADC

To guarantee that  $V_x$  always drop below  $V_{cm}$ , the input is limited to a certain range [9]

After preset 
$$V_x = V_{cm} + \left(\frac{C_2}{C_1 + C_2}\right)(V_{cm} - V_{in}) - \left(\frac{C_1}{C_1 + C_2}\right)V_{in} \quad (2.1)$$

$$V_x = \left(2 - \frac{C_1}{C_1 + C_2}\right)V_{cm} - V_{in} \quad (2.2)$$

In the case of 
$$0 \leq V_x \leq V_{cm} \quad (2.3)$$

then 
$$\frac{1}{2}V_{cm} \leq V_{in} \leq \frac{3}{2}V_{cm} \quad (2.4)$$

This limits the input range to at most only half full scale. This limitation causes problem for  $\Delta\Sigma$  modulator, which is discussed in chapter 4.

## Chapter 3

### An Op-Amp Based $\Delta\Sigma$ Ideal Circuit Design

The basic theory of the comparator-based switched-circuit (CBSC) is explained in Chapter 2. The next step is to apply this theory to a practical design of a 2<sup>nd</sup>-order  $\Delta\Sigma$  modulator. This chapter provides a brief overview of a particular op-amp based  $\Delta\Sigma$  modulator structure that is being converted to a CBSC version.

#### 3.1 Operation and Architecture

$\Delta\Sigma$  modulation is based on the technique of oversampling to reduce the noise in the band of interest (left shaded area of Fig. 3-1 [7]), which also avoids using high-precision analog circuits for the anti-aliasing filter [7]. Another important property of  $\Delta\Sigma$  modulator is noise shaping. For a first order  $\Delta\Sigma$  modulator, noise is being shaped by the function  $H_1(z) = 1 - z^{-1}$ ; for a n<sup>th</sup> order  $\Delta\Sigma$  modulator, noise is being shaped by the function  $H_n(z) = 1 - z^{-n}$ , resulting in in-band quantization noise variance to equal to  $e_{rms} \frac{\pi^n}{\sqrt{(2n+1)}} \left(\frac{1}{OSR}\right)^{\frac{2n+1}{2}}$  [7], where  $OSR$  represents the oversampling rate. On the system level, there are many ways to realize a  $\Delta\Sigma$  modulator. Richard Schreier has provided a very convenient MATLAB tool box “delsig” (available at

www.mathworks.com/matlabcentral/fileexchange) to calculate the coefficients for various orders and types (feed-forward, feed-back etc.).

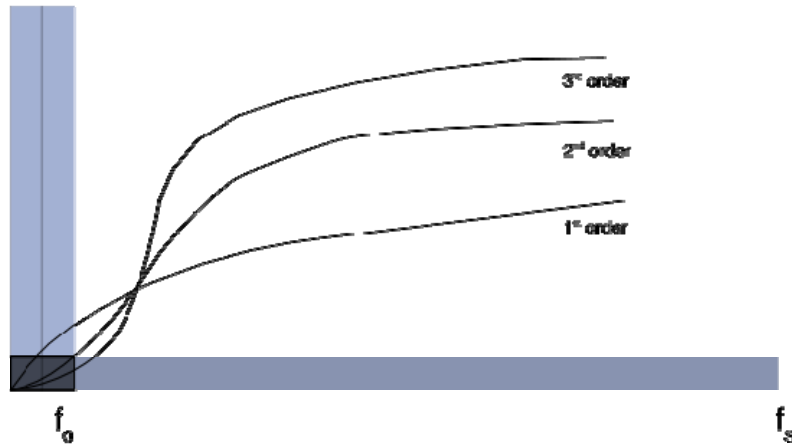


Figure 3-1: Noise shaping curves and noise spectrum in  $\Delta\Sigma$  modulator

For this project, a commonly used 2<sup>nd</sup>-order feed forward  $\Delta\Sigma$  modulator is chosen, with system level block diagram shown in Fig. 3-2. Each  $\frac{z^{-1}}{1-z^{-1}}$  block can be modeled as a delay unit with feedback, which represents an integrator:  $y(n) = y(n - 1) + x(n - 1)$ . The coefficients, listed in Table 3-1, are chosen to make sure that the voltage swing at each stage is well within range of Vdd (2V) and Vss (ground). The overall DC gain of the modulator is  $\frac{1}{2}$  (see Appendix A.4 for mathematical calculation). The signal transfer function (STF) and noise transfer function (NTF) of this modulator are shown in Fig. 3-3.

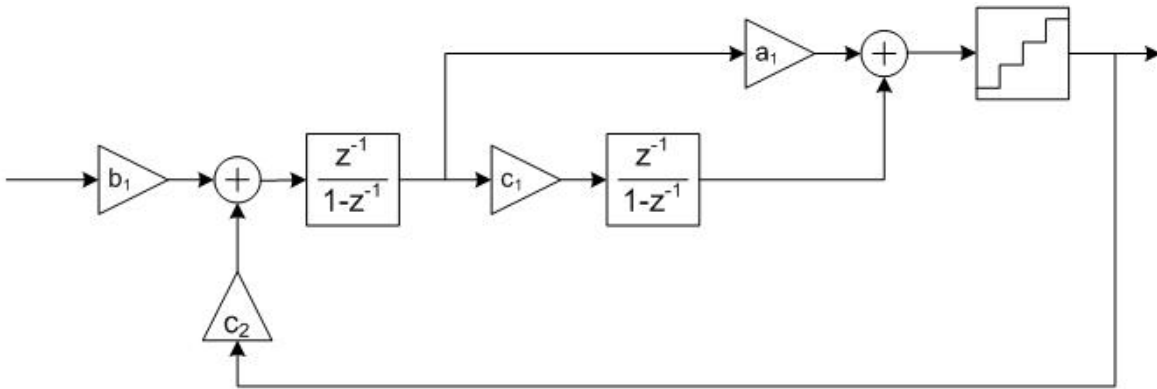


Figure 3–2: Block diagram of a 2<sup>nd</sup>-order feed-forward  $\Delta\Sigma$  modulator

Table 3–1: Coefficient values

Coefficient	Value
$a_1$	1
$b_1$	$\frac{1}{3}$
$c_1$	$-\frac{2}{3}$
$c_2$	$\frac{1}{2}$

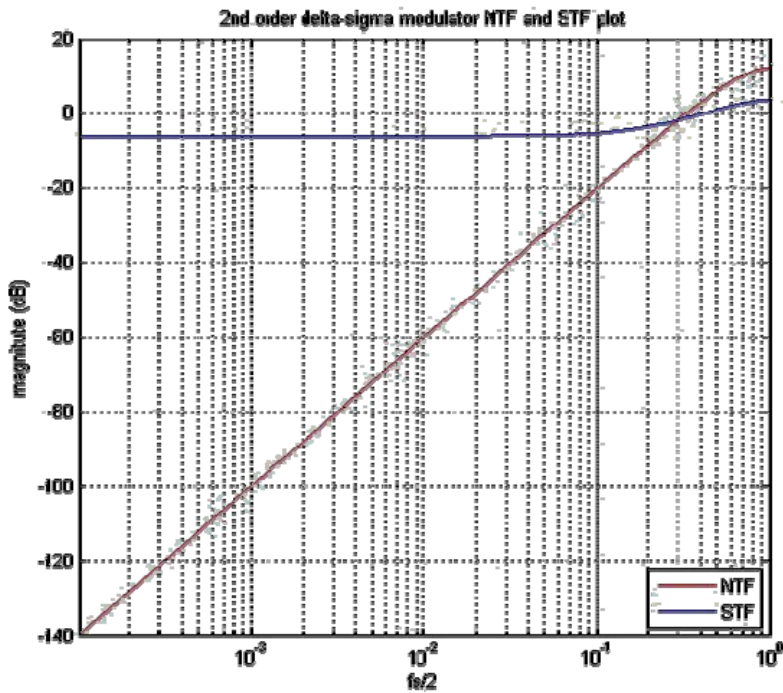


Figure 3–3: NTF and STF plot for 2<sup>nd</sup> order  $\Delta\Sigma$  modulator

### 3.2 Circuit Implementation

The top level block diagram of the op-amp based  $\Delta\Sigma$  modulator is shown in Fig. 3-4, and the top level schematic is shown in Fig. 3-5. The first block is a delayed integrator (*intg1*) with a simple built-in digital-to-analog convertor (*DAC*) to convert the digital output of the quantizer to certain voltage. The second block is a delayed integrator (*intg2*) with a non-delayed feed-forward path. The third block is a quantizer (*qtzr*) with gain of 3.

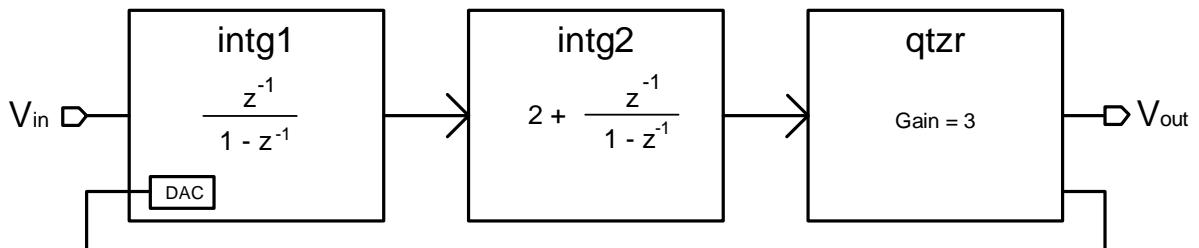


Figure 3–4: Op-amp based  $\Delta\Sigma$  modulator block diagram

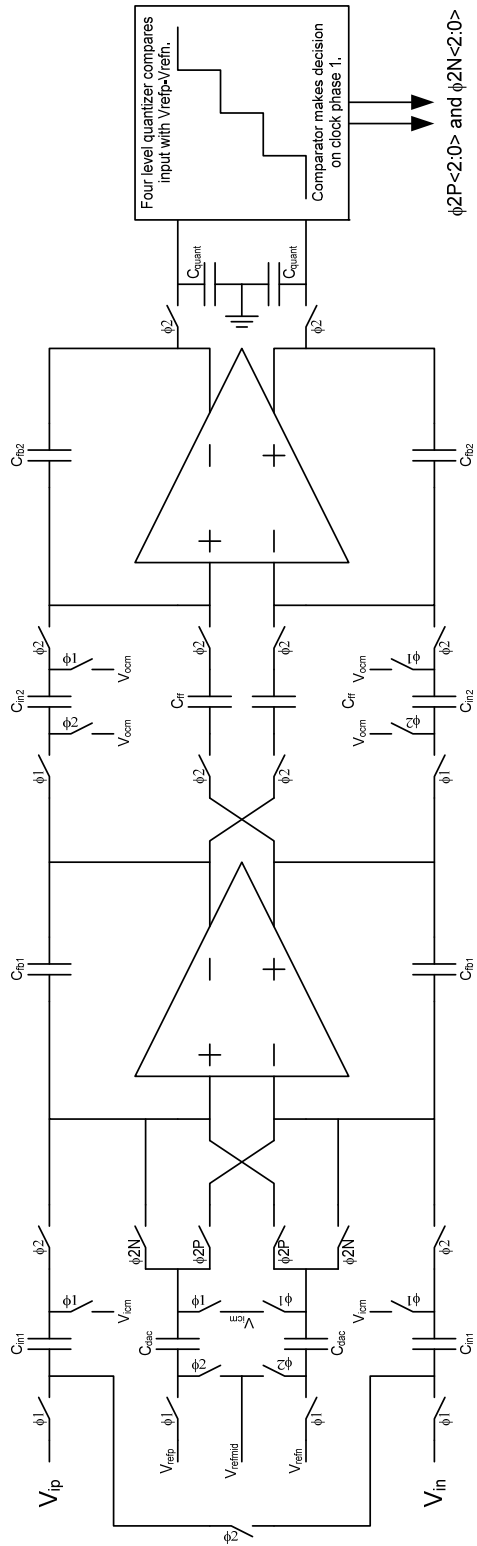


Figure 3–5: Top level Schematics of an op-amp based 2<sup>nd</sup> order  $\Delta\Sigma$  modulator

In the op-amp based design, analog data is being converted to digital data after two and a half cycles. Each cycle has two non-overlapping clocks, phase-1 and phase-2, as in Fig. 3-6. For the first cycle, *intg1* samples from the input and the output from *DAC* during phase-1, and integrates during phase-2. The output of *intg1* becomes available by the end of phase-2. For the second cycle, the delayed integration path samples previous cycle's *intg1* output data during phase-1, and integrates the data during phase-2. On the other hand, the non-delayed feed-forward path directly passes the *intg1* output data of the current cycle during phase-2 to the output. The outputs of both paths become available by the end of phase-2 of the second cycle. In the meantime, *qtzr* samples the outputs of *intg2* during phase-2 of the second cycle, and outputs logic signal during phase-1 of the next cycle, which is being fed back to the *DAC* of *intg1*. The modulator then keeps repeating the above process.

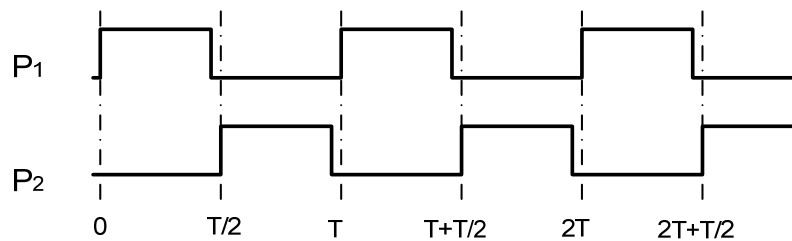


Figure 3–6: non-overlapping clock, phase-1 (P1) and phase-2 (P2)

As mentioned in chapter 1, op-amps are not very power efficient for modern switched-capacitor circuit design. Chapter 4 describes a comparator-based attempt to build this 2<sup>nd</sup> order  $\Delta\Sigma$  modulator with lower power.



## Chapter 4

### CBSC 2<sup>nd</sup> Order $\Delta\Sigma$ Modulator

Mathematically, the CBSC block works pretty much the same as an op-amp; however, there are many differences when it comes to circuit design. This chapter describes some changes made to the basic 2<sup>nd</sup> order  $\Delta\Sigma$  Modulator structure, and the implementation of a CBSC version.

#### 4.1 Differential CBSC without Preset Phase

In order to get better performance, a differential version is designed based on the original single-ended CBSC circuit. It is very easy to get a pseudo differential version. Imagine that there are two inputs at the input of two identical single-ended CBSC integrators: the input at  $V_{xp}$  is initially larger than input common mode voltage ( $V_{cm}$ ), and the input at  $V_{xn}$  is smaller than  $V_{cm}$ . The resulting  $V_{xp}$  and  $V_{xn}$  voltages are shown in Fig. 4-1 a). Put the two single-ended CBSC blocks together, Fig. 4-1 b), we get a pseudo differential version, Fig. 4-2 [10].

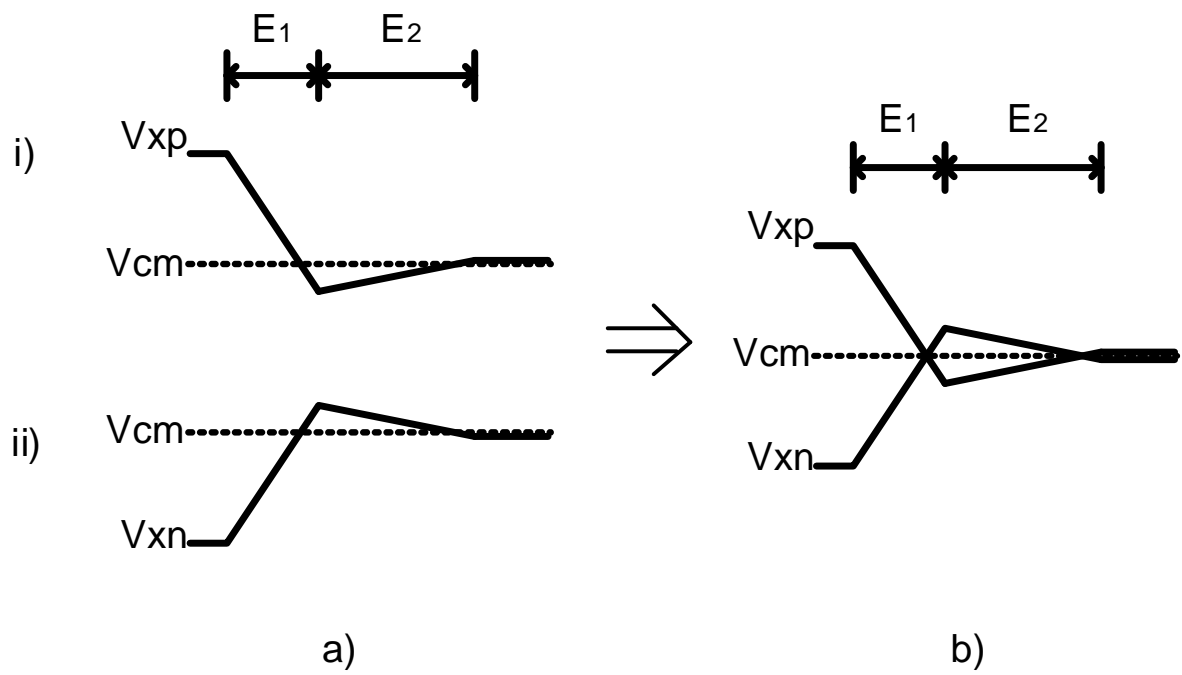


Figure 4-1: Single ended to differential conversion

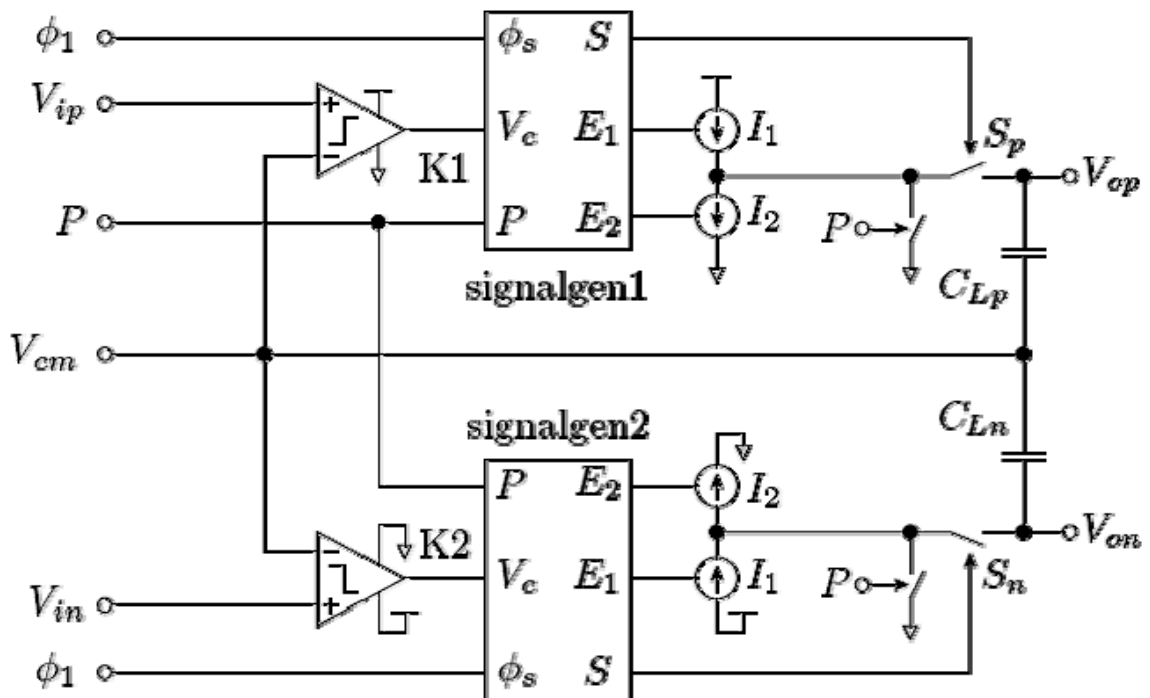


Figure 4-2: Pseudo differential design [7]

However, this design has a few problems. The positive branch and the negative branch are completely independent of each other. Any mismatch or delay will cause the two branches to act differently and as a result the input and output common mode voltage will be shifted. Also, the normal output common mode voltage regulation circuits cannot be used for CBSC circuits [4]. Drifting common mode voltages will eventually drive the outputs towards one of the rails and disable the modulator. Additionally, preset phase does not work very well for this differential modulator. Recall that the whole purpose of preset phase in the original CBSC design is to pull  $V_x$  below  $V_{cm}$ , Fig. 2-3. In the pipelined ADC design in section 2-3, the CBSC block is used to provide a constant gain. During the sampling phase, the feedback capacitor is reset each period. In this pipelined ADC case, the condition is easier to predict:  $V_x$  drops below  $V_{cm}$  as long as the input is within  $\frac{1}{2}V_{cm} \leq V_{in} \leq \frac{3}{2}V_{cm}$ . However, in a  $\Delta\Sigma$  modulator, the situation is more complicated. The CBSC block is used in an integrator. Its feedback capacitor never gets reset. In this case,  $V_x$  is affected by both the input and the output voltages. For an integrator, in order to make sure  $V_x$  drops below  $V_{cm}$  after preset, the following equations need to be satisfied (see Appendix A-2 for detailed calculations):

$$(C_1 + C_2)V_x(nT + P) = -C_2V_{in}(nT) - C_1V_o(nT) + (C_1 + 2C_2)V_{cm} \quad (4.1)$$

$$V_{cm} - V_x(nT + P) = \frac{(-C_2(V_{in}(nT) - V_{cm}) + C_1V_o(nT))}{C_1 + C_2} \geq 0 \quad (4.2)$$

$$V_o(nT) \geq \frac{C_2}{C_1}(V_{in}(nT) - V_{cm}) \quad (4.3)$$

$$V_o(nT) \geq \frac{C_2}{C_1}V_{diff}(nT) \quad (4.4)$$

The condition in *equation 4.4* is not always true in a  $\Delta\Sigma$  modulator, and the modulator will fail to operate. A more robust design is needed for  $\Delta\Sigma$  modulator. Because the preset phase can no

longer do the job it supposed to, it is taken out of the design. Instead, a second set of current sources are added so that it works regardless of the input combinations, as seen in Fig. 4-3. If  $V_{xp} > V_{xn}$ , then the  $E_{1p} - E_{2p}$  set is being used to source current; if  $V_{xp} < V_{xn}$ , then the  $E_{1n} - E_{2n}$  set is being used to sink current. See section 4-7 for details about the current source.

Calculations in Appendix A.3 show that there is no theoretical difference between the revised CBSC block without preset phase and the original CBSC block with preset phase.

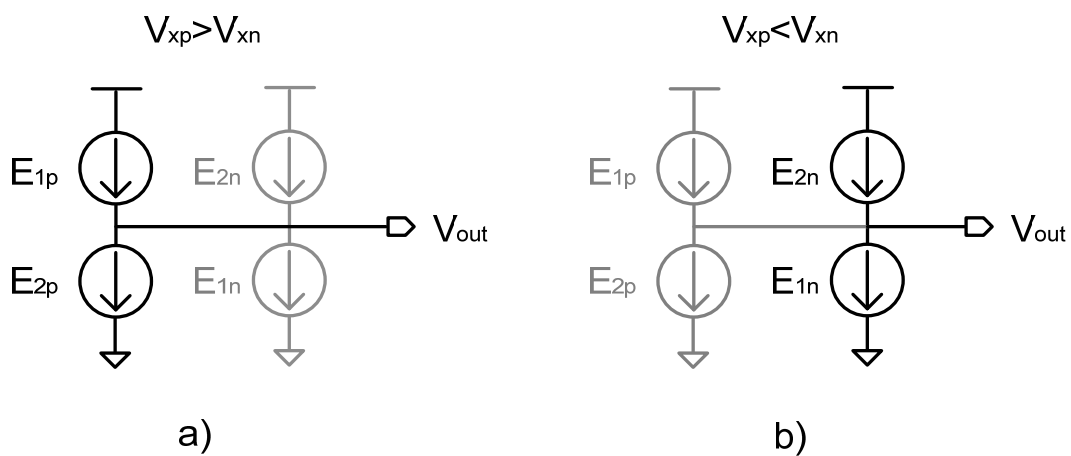


Figure 4–3: Additional set of current source branch helps to make the CBSC operate without constrain on the input range

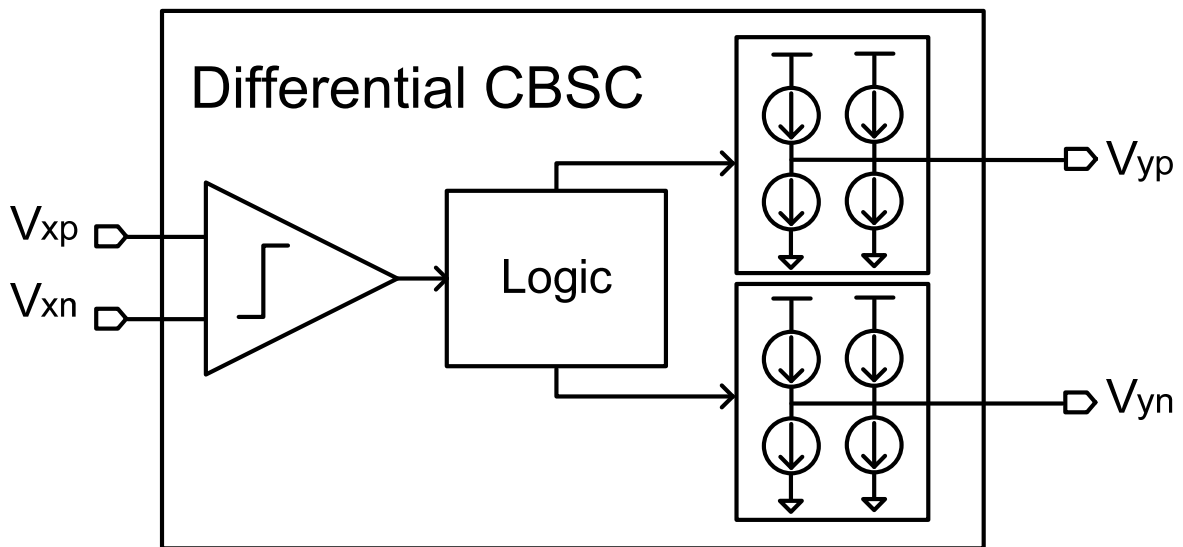


Figure 4–4: Differential CBSC Block Diagram

## 4.2 CBSC Feed-Forward Path Issue

Even though the CBSC circuits behave similarly as the op-amp circuits do, but there is a fundamental difference: CBSC circuits cannot support a feed-forward path, which is commonly used in op-amp circuits. To illustrate this difference, Fig. 4-5 shows a feed-forward path between *intg1* and *intg2*, with CBSC block replacing op-amp. Originally, this feed-forward path works fine with op-amps, because op-amps can provide current at all time. Also, op-amp based integrators do not care how the currents are moving as long as they eventually settle. However, CBSC blocks are very sensitive to the movements of currents and the change of voltage at its input. As it shows in Fig. 4-5 a), the feed-forward path between *intg1* and *intg2* causes conflict between current  $I_1$  and  $I_2$  at the capacitors between them.

Also, depending on the input at each integrator, *intg1* and *intg2* may finish integrating at different times. Once the integration of *intg1* finishes, current sources of the CBSC block in *intg1* is shut off, disconnecting the load capacitors, which are also the input sampling capacitors of *intg2*, Fig. 4-5 b). The charge is no longer available for the feed-forward path. On the other hand, op-amp based integrator can function with the feed-forward path in *intg2*, because the op-amp can provide output current at any time as long as the input is not disturbed.

In conclusion, the CBSC based *intg2* cannot be used as a summer like the one in an op-amp based *intg2*. To solve this problem, the feed-forward path is separated from *intg2*, so that there is no summation in *intg2*. Instead, *qtzr* samples results from *intg1* directly during phase-2, and combines that result with *intg2* output. Fig. 4-6 is the updated system block diagram. It is desired to compare the sum of the differential outputs of the two integrators,  $(V_{intg1p} -$

$V_{intg1n}) + (V_{intg2p} - V_{intg2n})) = (V_{intg1} + V_{intg2})$ , with the three reference levels of the quantizer:  $(V_{thp} - V_{thn})$ , 0, and  $(V_{thn} - V_{thp})$ .

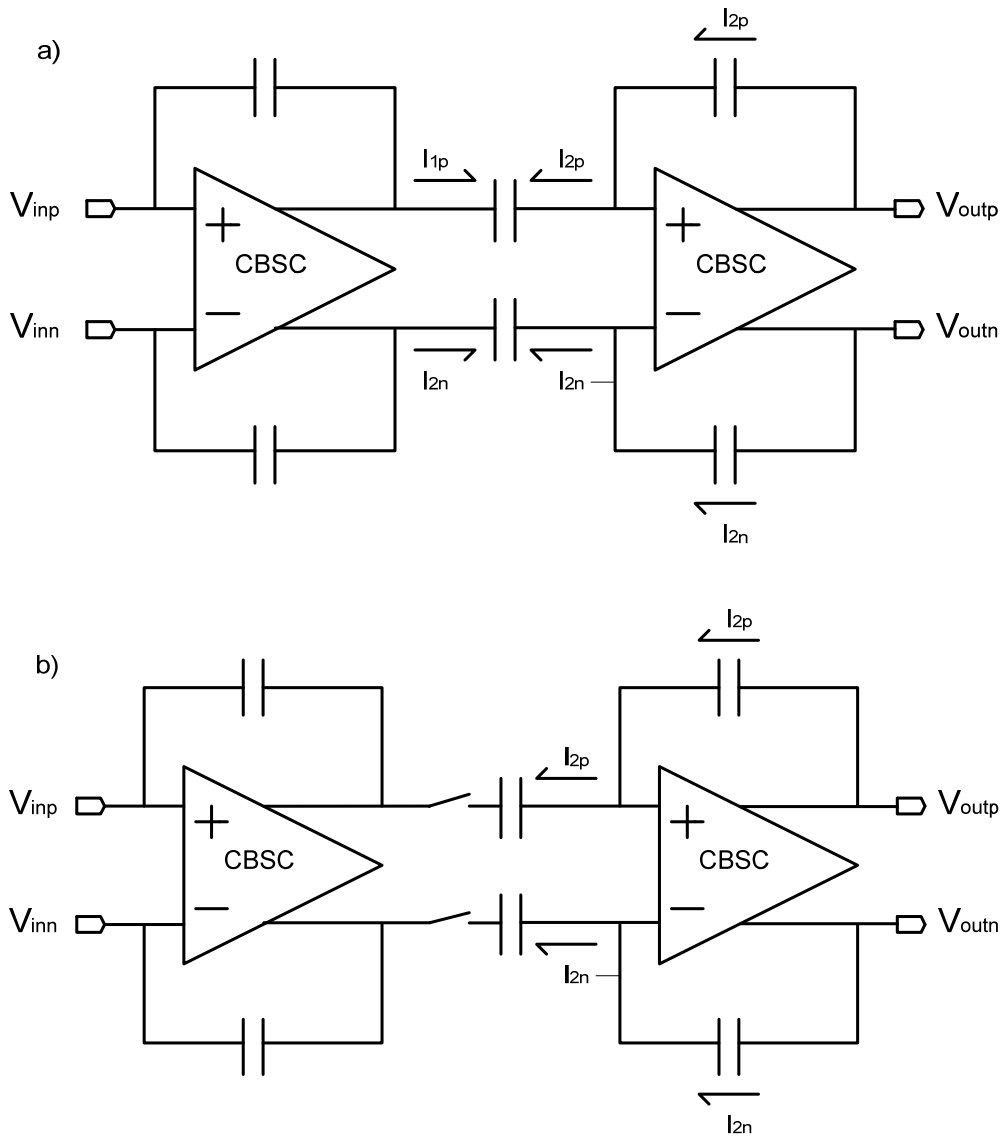


Figure 4-5: Current conflict between two CBSC driving stages

Three latched comparators are used in the quantizer, *Figure 4-7*. Their outputs follow the following equation:

$$Q = \text{sinh} \left( (V_{inp} - V_{inn}) - (V_{refp} - V_{refn}) \right) \quad (4.5)$$

If  $Q$  is positive, the comparator outputs logic high; if  $Q$  is negative, the comparator outputs logic low. For example, in order to compare  $(V_{intg1} + V_{intg2})$  with  $(V_{thp} - V_{thn})$ , the quantizer needs to sample the outputs in a way that:

$$Q = \text{sign} \left( (V_{intg1} + V_{intg2}) - (V_{thp} - V_{thn}) \right). \quad (4.6)$$

Fig. 4-8 a) and c) demonstrates the circuit implementation. It is easy to confirm that

$$V_{c1p} = V_{thn} - (V_{intg1n} - V_{icm}) \quad (4.7)$$

$$V_{c1n} = V_{thp} - (V_{intg1p} - V_{icm}) \quad (4.8)$$

$$V_{c3p} = V_{ocm} - (V_{intg2n} - V_{icm}) \quad (4.9)$$

$$V_{c3n} = V_{ocm} - (V_{intg2p} - V_{icm}) \quad (4.10)$$

The desired comparison is obtained by connecting  $V_{c1p}$  to  $V_{inp}$  pin of the latched comparator, and  $V_{c1n}, V_{c3p}, V_{c3n}$  to  $V_{inn}, V_{refp}, V_{refn}$  pins respectively. The other two comparisons can be arranged in the similar manner.

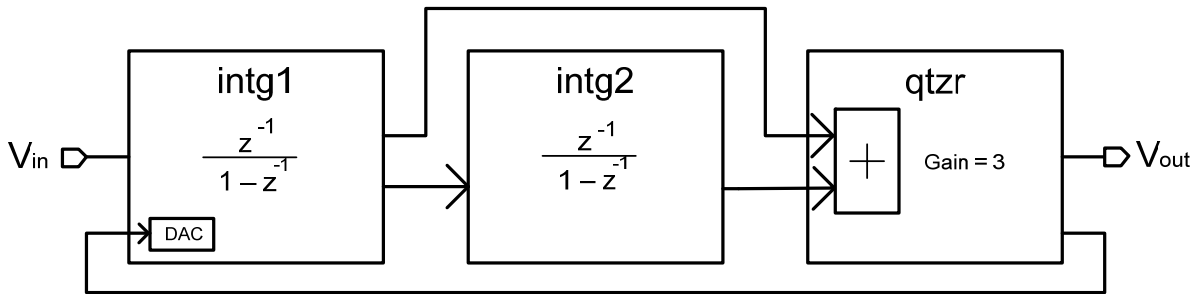


Figure 4–6: CBSC  $\Delta\Sigma$  modulator block diagram

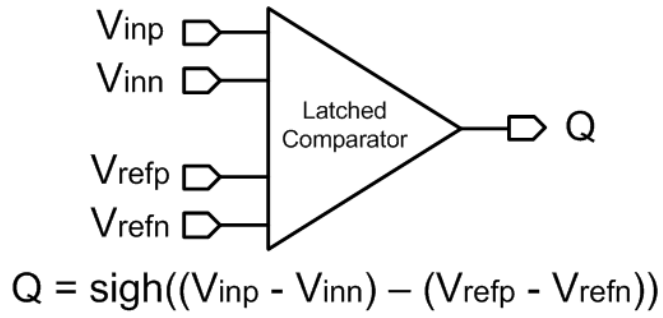


Figure 4–7: Latched comparator used in quantizer

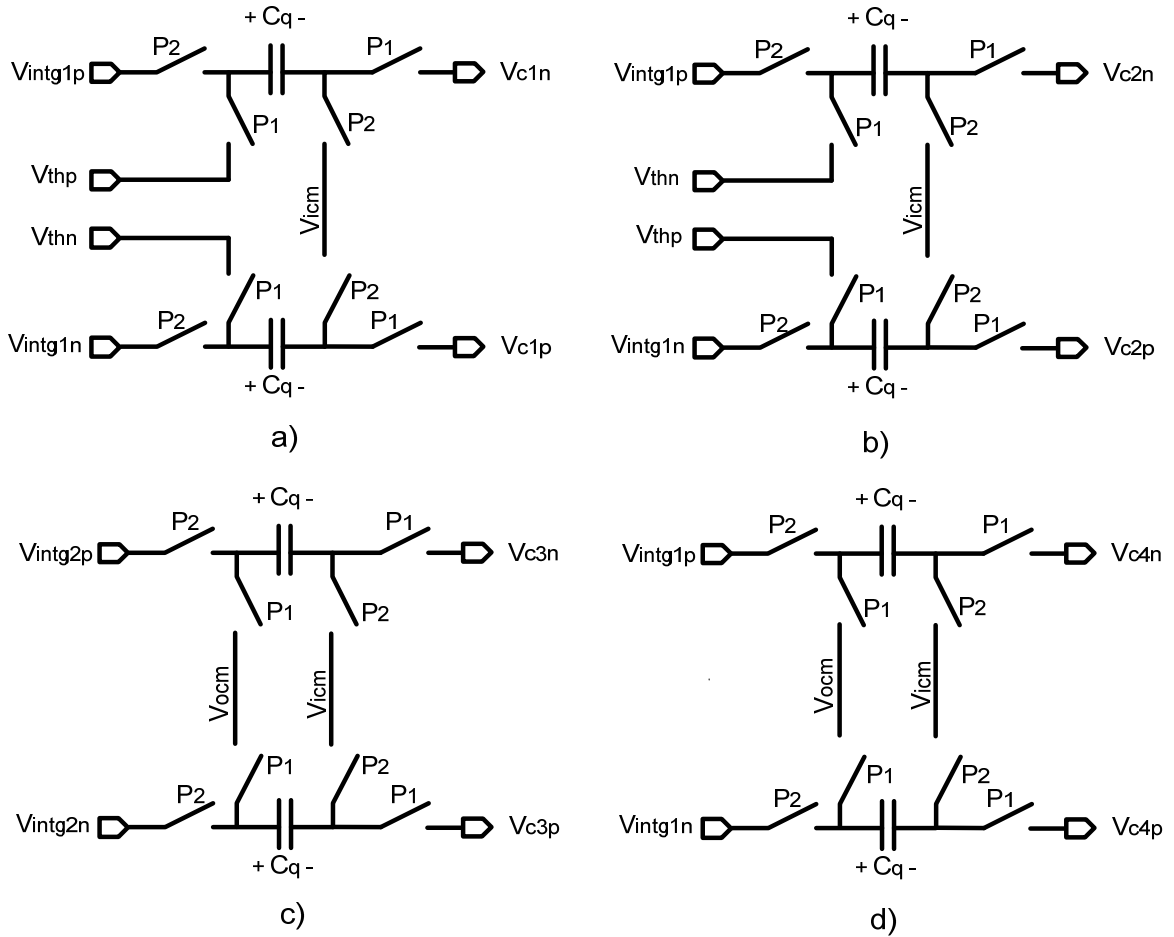


Figure 4–8: Sampling capacitor setups for quantizer



### 4.3 $z^{-\frac{1}{2}}$ Delay

The second problem is that the output of CBSC integrator is only available during the integration phase, phase-2. During the sampling phase, phase-1, the loading capacitor is floating, and the CBSC block is unable to provide any charge for the next stage to sample. It means that *intg2* cannot sample the *intg1* outputs during phase-1, as it does in the op-amp based modulator.

To solve this problem, dummy branches are added to *intg1* to realize a half cycle delay,  $z^{-\frac{1}{2}}$ . Fig. 4-9 shows a simplified single ended version of *intg1* with added dummy branch. This dummy branch samples zero as its input during phase-2, and integrates zero during phase-1. This operation would not change the previous result of  $V_{out}$ , but it provides current for the next stage to sample during phase-1. However, because integration happens twice, the overshoot error is created both times. Effectively, the overshoot error doubles, which is a drawback of this structure. It also draws more power because of the additional integration.

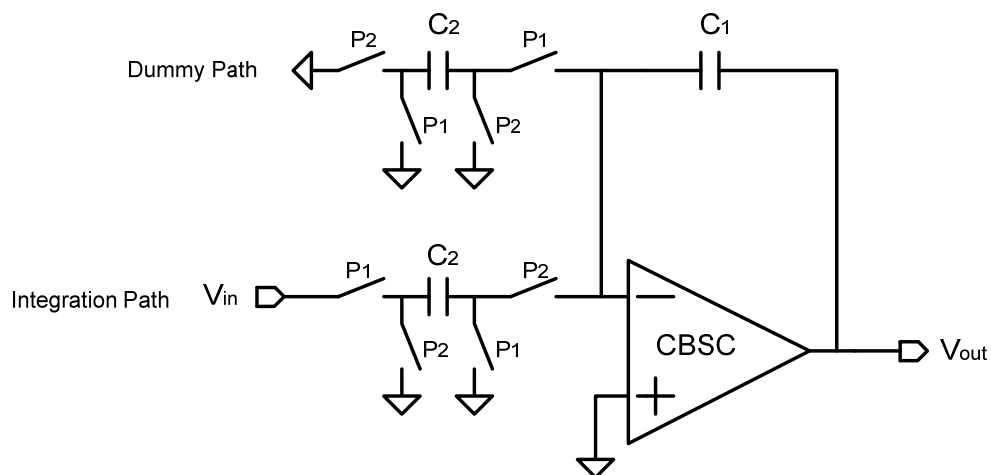


Figure 4–9: Single ended version of *intg1* with dummy branch

## 4.4 Capacitor Sizing

There are a few factors that affect the sizing of the sampling capacitors in this modulator. One dominant factor is the thermal noise associated with the capacitors of the first stage, *intg1*. The

thermal noise power can be estimated by  $n_{thermal}^2 = \frac{1}{OSR} \frac{4KT}{C_{in}} \left(1 + \frac{C_{dac}}{C_{in}} + \frac{C_{dummy}}{C_{in}}\right)$  (see

Appendix A.6 for the mathematical calculation), where  $\frac{C_{dac}}{C_{in}} = 2$  for modulator coefficients,

$\frac{C_{dummy}}{C_{in}} = 3$  to match the input capacitors, and *OSR* equals to 250 in this CBSC  $\Delta\Sigma$  modulator.

To ensure that the thermal noise wouldn't be a dominate noise source, the signal to thermal noise

ratio should be at least 6 dB lower than signal to quantization noise ratio:  $10 \log_{10} \left( \frac{V_{in,rms}^2}{n_{thermal}^2} \right) >$

$(SNR_{quantization} + 6dB)$ . To be safe,  $SNR_{quantization}$  is set equal to 86 dB. SNR here is set to

smaller than SNR of a traditional op-amp based modulator due to the limitation of a CBSC based

modulator. Then plug in values and solve,  $C_{in}$  is found to be bigger than 1.2pF. The capacitors in

*intg2* do not contribute as much input referred thermal noise, which means that the capacitors in

Table 4–1: capacitor sizing

Capacitor	Description	Value
$C_{in1}$	input sampling capacitor for <i>intg1</i>	1.8 pF × 2
$C_{DAC}$	DAC sampling capacitor for <i>intg1</i>	1.2 pF × 6
$C_{fb1}$	feedback capacitor for <i>intg1</i>	5.4 pF × 2
$C_{in2}$	input sampling capacitor for <i>intg2</i>	1.35 pF × 2
$C_{fb2}$	feedback capacitor for <i>intg2</i>	2.7 pF × 2
$C_q$	input sampling capacitor for <i>qtzr</i>	1 pF × 8

intg2 could be even smaller. However, because leakage currents have greater effect on smaller capacitors than larger ones, the capacitors cannot be too small. Also, larger capacitors require larger current. As a result, the capacitor sizes are set as shown in Table 4-1 for a better overall performance of the modulator. The optimal values yet need to be found.

## 4.5 Sampling Switches

The switches of the sampling branches are mostly transmission gate, with characteristics shown in Fig. 4-10. The relative sizes of the p-mos and n-mos of the transmission gate control the on-resistance of the switch. In general, it is desired to make the peak of the on-resistance happen at the middle of the possible voltage range between  $V_{SS}$  and  $V_{DD}$ .

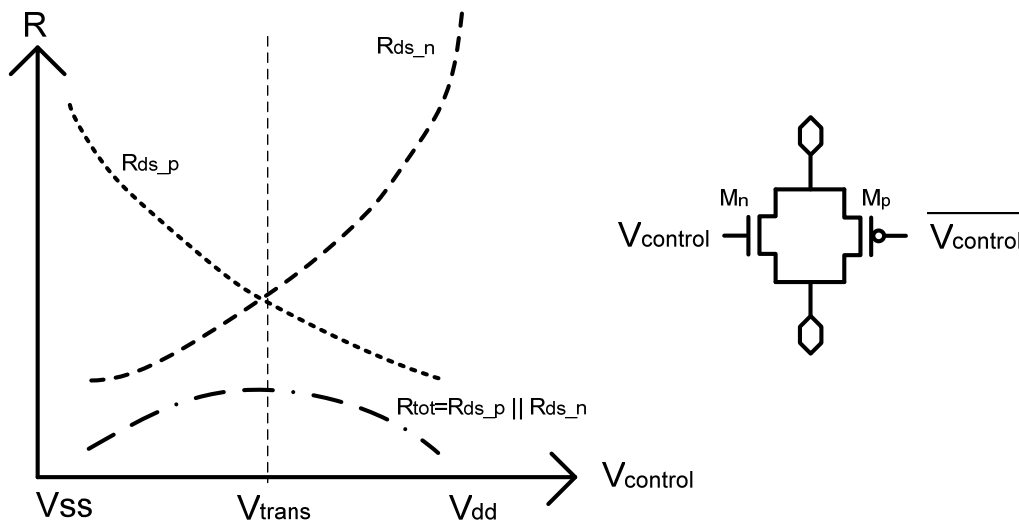


Figure 4–10: Demonstration of transmission gate on-resistance

There is one undesired effect of the switch on-resistance. Fig. 4-11 shows a simplified circuit to demonstrate this effect. The current source of the CBSC block is modeled as a simple current source with a step input. Once the current is turned on, a constant current goes through the resistor and charges the capacitor, which makes the voltage across the capacitor ramps up

linearly. The current also causes a voltage drop across the resistor, makes  $V_1$  steps up instantly, where  $V_1 = RI_o$ . This glitch can be ignored at any node of the circuit expect  $v_x$ , input node of the CBSC block. As it mentioned in previous section, the positive branch and negative branch are mirrors of each other.  $V_{xp}$  and  $V_{xn}$  travels in different direction, which means the glitch will cause the voltages at these two nodes either become farther apart (error1) or closer (error2) at the moment when the current sources are turned on or off, see Fig. 4-12 b). Error1 causes longer integration time. If the CBSC block takes too long then it may not be able to finish integrating before the end of the integration phase, very big overshoot error will result. Error1 is not recoverable and is not acceptable for for  $\Delta\Sigma$  modulator. Also, this glitch can cause false triggering, error2. This error causes the logic of CBSC circuit to stop providing current too early that E2 doesn't even start. Error2 causes larger overshoot error than expected.

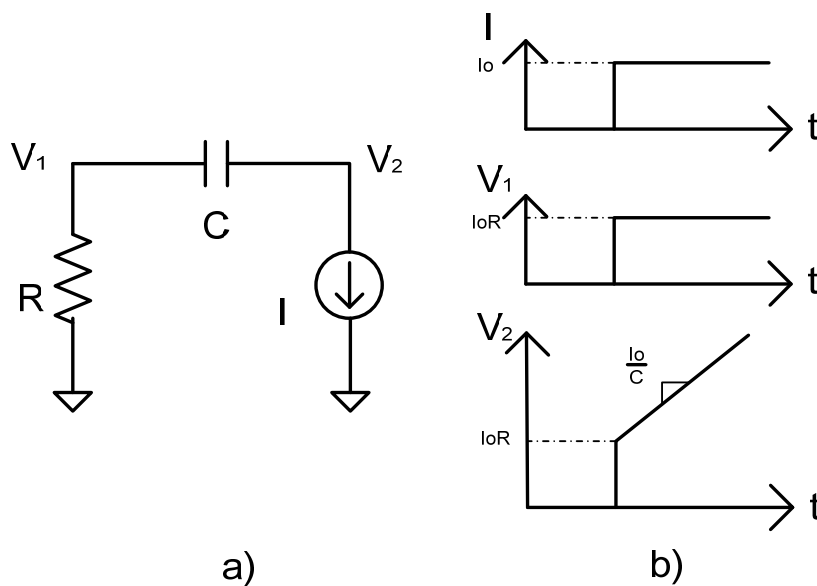


Figure 4–11: a sample RC circuit with step input current.

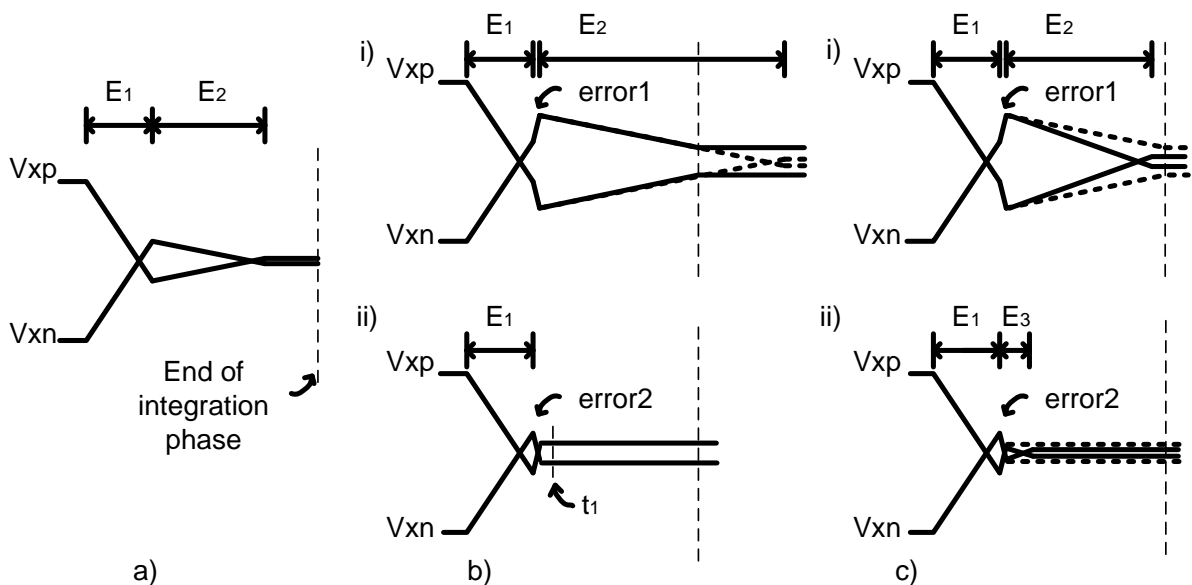


Figure 4–12: a) Ideal behavior of comparator input voltage. b) Two types of effect caused by on-resistance of the switch. c) Resulting behavior after error correction.

The error from on-resistance of the switch is inherent in the circuit and cannot be avoided.

To make sure the CBSC circuit finish integrating in error1 situation, a larger current during  $E_2$  is being used. This bigger  $E_2$  current will cause bigger overshoot than original, but it makes sure the integrator finishes integrating. As for error2, it is pretty easy to detect the happening of error2, because the glitch usually takes much shorter time than  $E_2$ . We can check the status of the current source at time  $t_1$  in Fig. 4-12 b): if  $E_2$  is on, then error2 will not happen; if  $E_2$  is not on, then error2 happens. Logic block is updated from the ideal version so that it can detect error2 and turn on the corresponding current,  $E_3$ , to pull  $V_{xp}$  and  $V_{xn}$  closer, see Fig. 4-12 c).

## 4.6 CBSC Logic Block

The CBSC logic block is the brain of the  $\Delta\Sigma$  modulator. It takes a comparator result as input, and outputs a signal to turn on or off the current sources. The logic for this proposed CBSC  $\Delta\Sigma$  modulator is represented in a state machine diagram in Fig. 4-13. In each state, the corresponding signal (named the same way as the state) goes high and the rest go low. When the CBSC block is in *Idle*, no current is provided. The integration phase clock acts as the start signal: depending on the comparator output, the state either goes to *E1p* (the top half path) or *E1n* (the bottom half path). Once the comparator output flips, the state goes to *E2* trying to correct the overshoot. Next, depending on whether the glitch (error2) in Fig. 4-12 b) happens, the state either goes back to *Idle*, or goes to *E3* to try to correct the overshoot again.

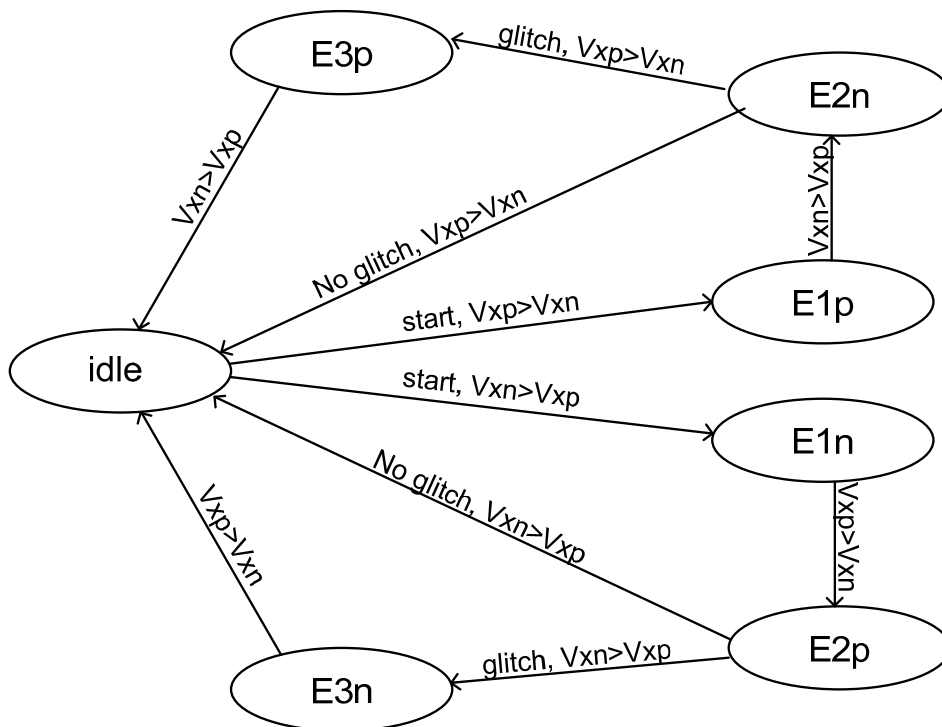


Figure 4–13: State machine diagram for logic block

As shown in the state machine diagram, it's the change of the comparator output values ( $V_{ad}$  or  $V_{ss}$ ) that triggers the change of states. In order to know which state is next, logic block needs to know what the current state is. For this purpose, set-reset flip flops (SR-FF) are used as counters. The operation of the SR-FF are summarized in Table 4-2 [8]. The reset (R) signal is the sampling clock for each SR-FF, so that the states are reset in *idle* state. The set (S) signal is the corresponding signal in each state. Once that signal goes high, the SR-FF is set and will not be reset till the next phase. For example, in order to create  $E_{1\_count}$  and  $E_{2\_count}$  signals to indicate that  $E_1$  or  $E_2$  have come up, the SR-FFs are connected as shown in Fig. 4-14 a), the outputs are shown in Fig. 4-14 b).  $E_{1\_count}$  and  $E_{2\_count}$  are low in the beginning. During  $P_2$ ,  $P_1$  remains low the whole time. Once  $E_1$  goes high, SR-FF set  $E_{1\_count}$  to high. After  $E_1$  drops low,  $E_2$  goes high, SR-FF set  $E_{2\_count}$  to high. Then,  $E_{1\_count}$  and  $E_{2\_count}$  remains high until  $P_1$  goes high to reset them. These output signals created by the SR-FF are good indications of whether certain state has occurred or not.

Table 4–2: Set-reset flip flop operation table [8]

SR Flip-Flop operation							
Characteristic table			Excitation table				
S	R	Action	Q(t)	Q(t+1)	S	R	Action
0	0	Keep state	0	0	0	X	No change
0	1	Q = 0	0	1	1	0	Set
1	0	Q = 1	1	0	0	1	Reset
1	1	Unstable combination, race condition	1	1	X	0	No change

('X' denotes a do not care condition; meaning the signal is irrelevant)

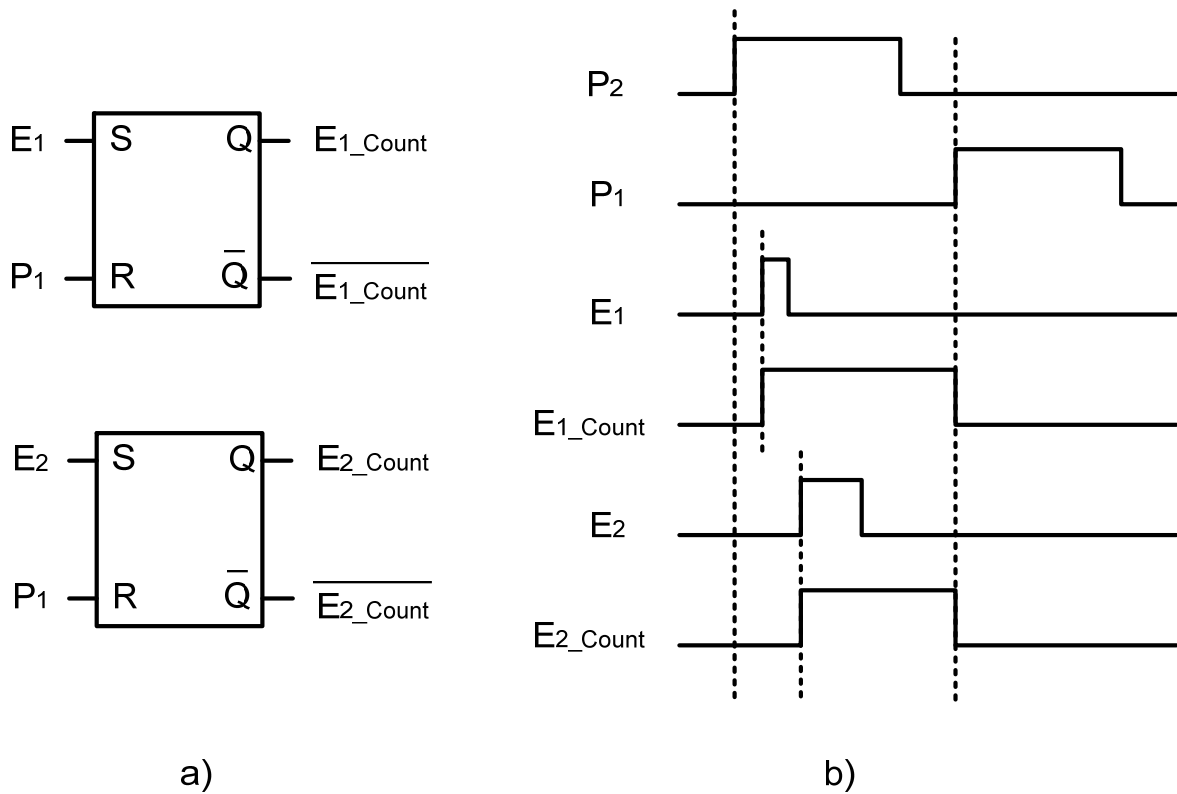


Figure 4–14: Example of the use of SR-FF. a) Set up. b) Resulting signal.

Notice that the conditions for state going from *Idle* to *E1n* and from *E1p* to *E2n* are pretty much the same. In order to prevent the state to go from *E1p* to *E1n* and *E2n* at the same time, the signal indicating that *E1p* has occurred is used to determine if *E1n* should be the next state or not.

The signals are created by common digital gates, such as and-gate, or-gate, and inverter, etc. They are all standard units. Because their real transistor level model behaves very similar to their Verilog behavioral models, Verilog behavioral models are used for convenience. The rise and fall time of the digital gates are set to 100ps.



## 4.7 Comparator

The comparator is one of the most important parts, because the comparator delay and decision error directly affects the performance of a CBSC block. Just the comparator alone can be expanded to a full PHD thesis. Due to the scope and purpose of this project, a simple 3-gain-stage comparator design is used.

As shown in Fig. 4-15, the comparator consists of three stages: differential amplification stage, differential to single ended amplification stage, and finally a common-source output stage. All three stages provide gain to make sure the comparator outputs full logic level even with very small differential input. One drawback of having multiple stages is that it is relatively slow, because there is cumulated delay from each stage. Each comparator draws about  $\sim 40\mu A$  current.

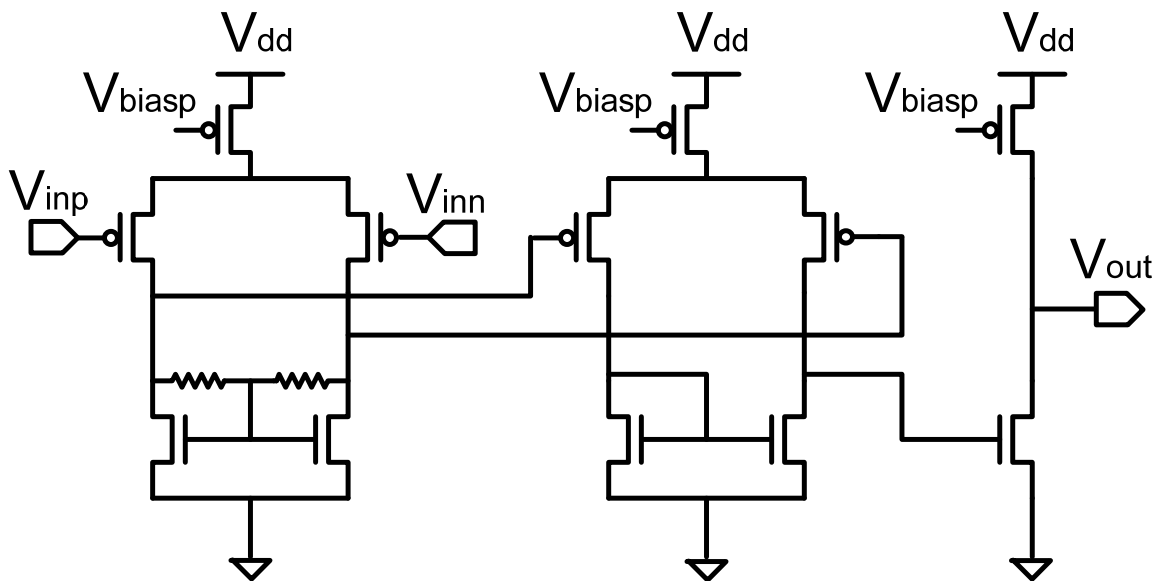


Figure 4-15: comparator design for CBSC block

In an op-amp based  $\Delta\Sigma$  modulator, op-amp offset voltage does not cause error; however, in a CBSC based design,  $V_{offset}$  directly causes error in CBSC block. For op-am based  $\Delta\Sigma$  modulator, this non-signal-dependent  $V_{offset}$  can be modeled as a constant input in the loop, Fig.

4-16. This constant input is suppressed by the modulator's loop gain and does not reduce modulator accuracy much at all. This conclusion is also verified by Matlab simulation. The simulation without manually added  $V_{offset}$  gets 114 dB SNR, while the simulation with manually added  $V_{offset}$  gets 112 dB SNR. The performance is almost the same. On the other hand, for a CBSC based design, the bigger the offset the bigger the integration error. Fig. 4-17 a) shows the expected behavior of the CBSC block without  $V_{offset}$ . With comparator offset, instead of comparing to  $V_{xn}$ ,  $V_{xp}$  compares to  $V_{xn} \pm V_{offset}$  and gives decisions at the wrong time. Fig.4-17 b) shows the resulting effects (exaggerated) caused by  $V_{offset}$ .  $V_{xp}$  and  $V_{xn}$  are not brought together as close as expected and causes bigger error.

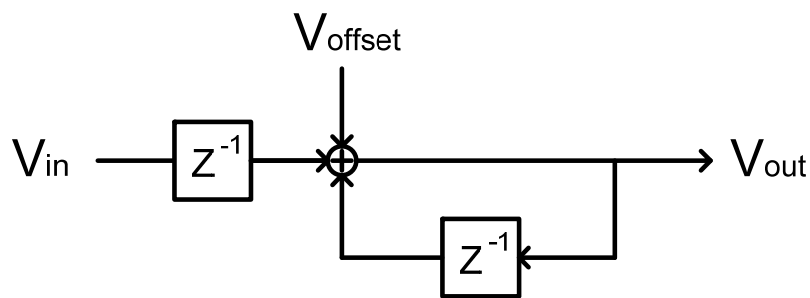


Figure 4–16: Model of comparator offset voltage

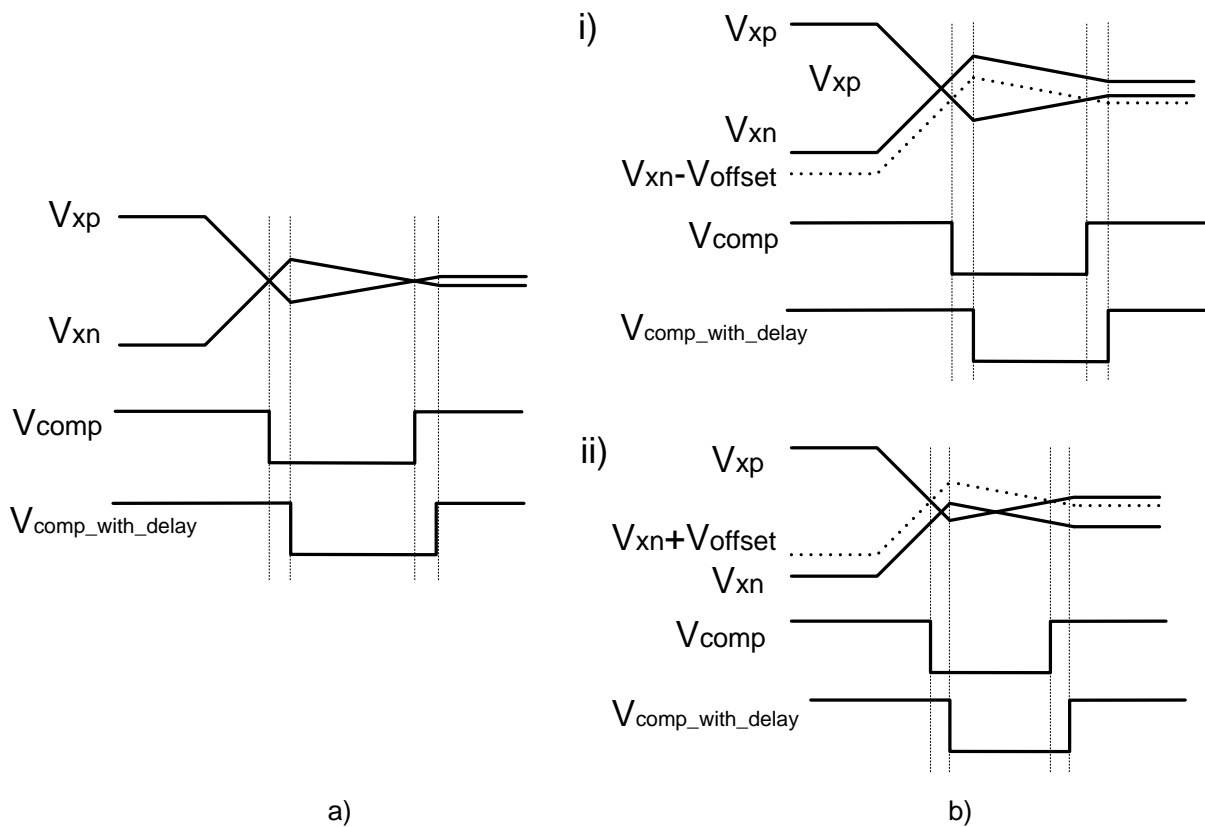


Figure 4–17: Error caused by comparator offset. A) Expected behavior. B) Error cases

The input referred offset voltage ( $V_{offset}$ ) of the comparator used in this project is about 2mV without mismatch. However, component mismatch is unavoidable in real process. Fig. 4-18 shows the statistic distribution of  $V_{offset}$  when there is mismatch. Even though  $V_{offset}$  is centered around 1mV, it has a very wide variation. Optimization for comparator  $V_{offset}$  and delay is definitely needed for a high precision CBSC  $\Delta\Sigma$  Modulator.

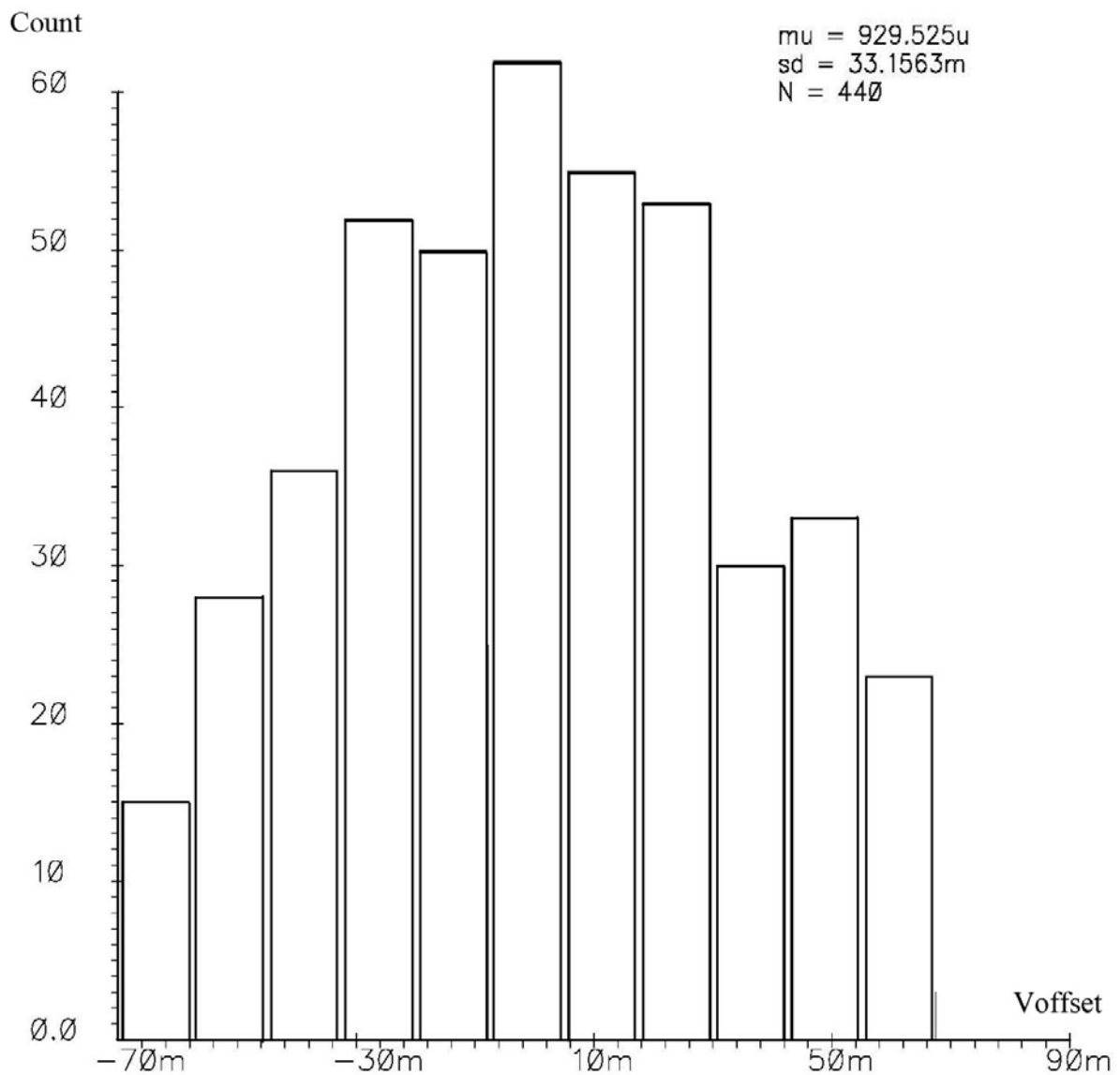


Figure 4-18: Comparator offset distribution

## 4.8 Current Source

The current sources either source current to or sink current from the rest of the circuit in order to bring the two input nodes of the comparator ( $V_{xp}$  and  $V_{xn}$ ) closer.

The initial design is to use cascode current mirror with switches to turn each branches on or off. Fig. 4-19 demonstrates how to turn a branch on and off. When signal  $E_1$  is high  $E_{1\_bar}$  is

low, the output branch is properly biased and provides current. When  $E_1$  is low and  $E_{1\_bar}$  is high, the corresponding switch closes and pulls the gate voltage of  $M_4$  to  $V_{dd}$ . As a result, the current of the output branch is turned off.

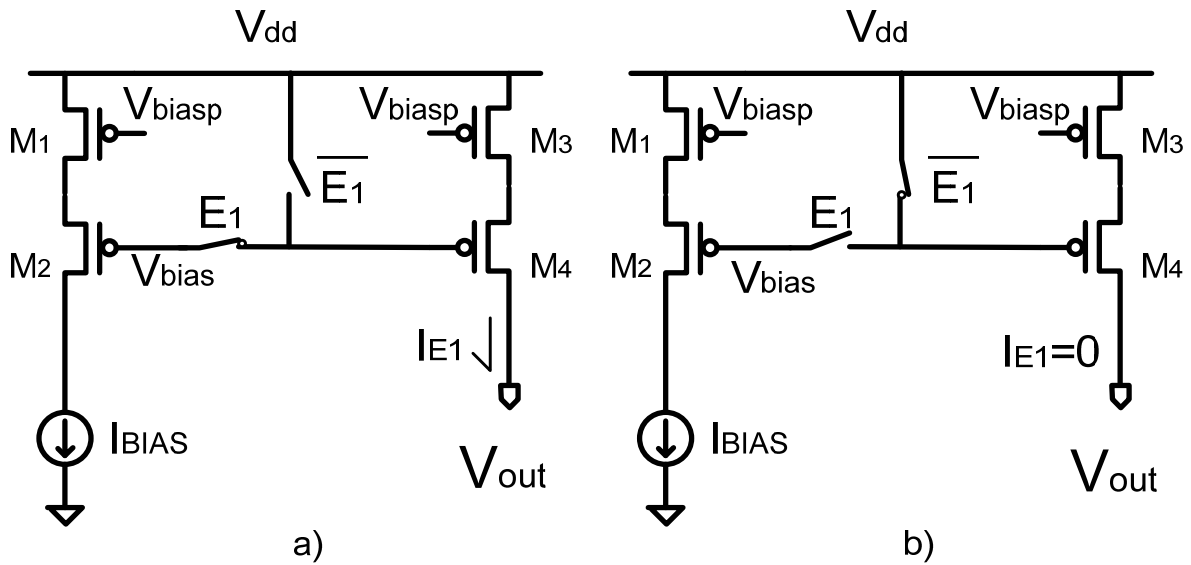


Figure 4-19: Initial design of current mirror. A)  $E_1$  high, current source is on. B)  $E_1$  low, current source is off.

There are a few issues with this design. The desired gate voltage of  $M_4$  is around 1.2V when current source is turned on, and  $V_{dd}$  (2V) when current source is turned off. In another words, at the moment of current source turned on or off, the gate voltage swings between 1.2V and 2V, this is a pretty big swing. As a result, it requires a lot of charge to charge or discharge the parasitic capacitances at the gate of  $M_4$ . It takes quite some time to settle to the desired value. The sudden change of bias voltage also creates large overshoot as shown in Fig. 4-20. As it is mentioned in chapter 2, the CBSC overshoot error is proportional to comparator delay and current source value. Therefore, if the output current cannot settle to the expected value before it turns off, an undesired large CBSC overshoot error will be created as a result.

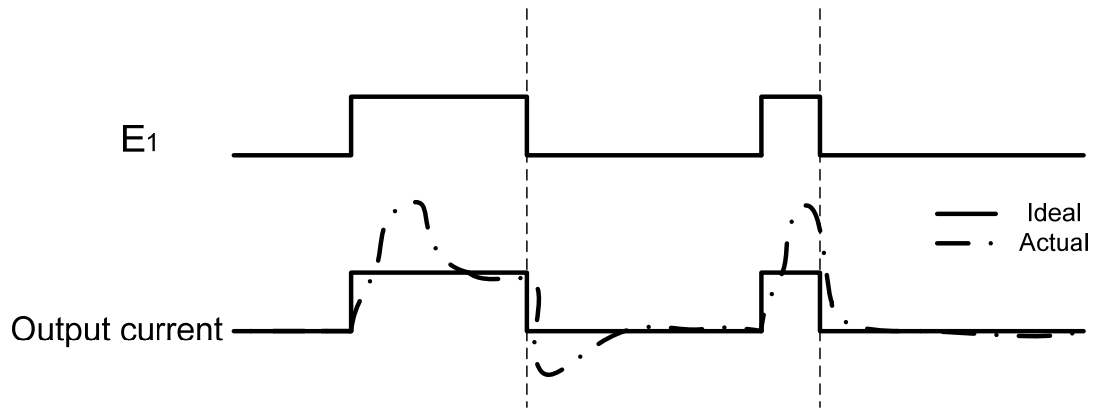


Figure 4–20: Comparison between the ideal current source and actual current source output currents

An alternative design used in the final version is a charge-pump style current source. The basic idea is presented in Fig. 4-21. The bias current is made by a simple current mirror instead of a cascode current mirror, because maximum output swing is desired. The bias current is on at all time, and the current is being steered to the desired output based on the switch signals. At the end of integration of the CBSC integrator, instead of being shut down completely, the current directly goes to ground (or  $V_{SS}$  of the circuit) through an internal path, so that effectively there is no current circulation in the external circuit.

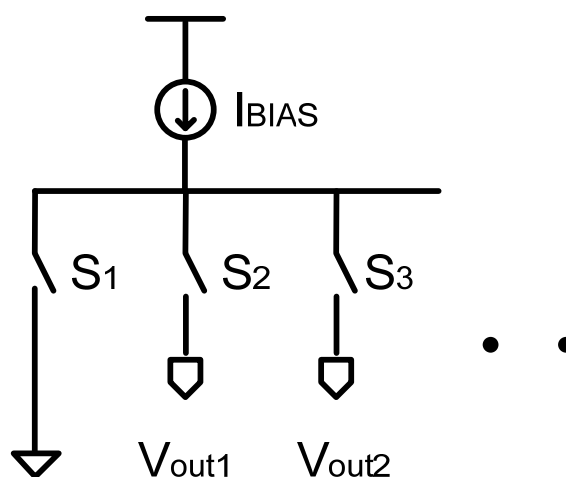


Figure 4–21: basic structure of charge-pump style current source

This charge-pump style current source can reach its desired value much faster than the switched current mirror version. Because the charge-pump style current source doesn't change any bias voltage of the bias current during transition, it avoids the large overshoot and long settling time.

One thing to be aware of is that at least one of the switches in the charge-pump style current source has to be on at any given time, in order to provide a complete path for the current. The switches are transmission gates with very large off-resistance (on the order of mega ohms). If all the switches are off, Fig. 4-22, the bias current goes through the large off-resistance, voltage at node-1 will instantly raise to  $v_{dd}$ . At that instant, the branch will be effectively shut off and will act the same as the previous described current mirror, which is not good. Therefore, the switch signals need to match each other in a way that they always meet each other at the mid-point voltage ( $v_{tran} = \frac{v_{dd} + v_{ss}}{2} = 1V$ ) at about the same time, as shown in Fig. 4-23. At that moment, all the paths are partially on with the on-resistance of the transmission gate at approximate the maximum value.

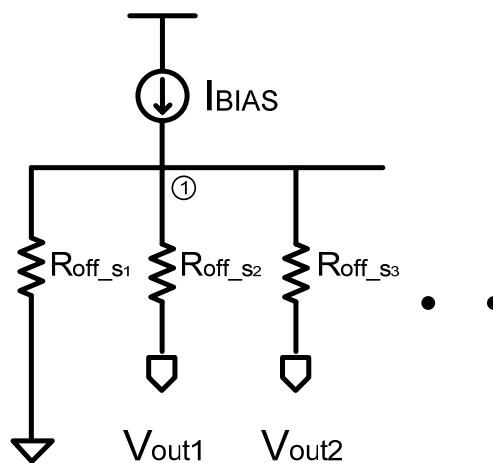


Figure 4–22: Equivalent circuit of charge-pump style current source when all the branches are off.  $R_{off}$  is on the order of mega ohms

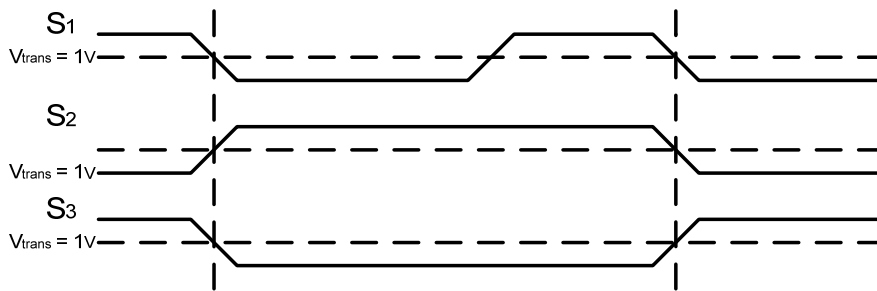


Figure 4–23: Switch signals needs to match so that they reach  $V_{trans}$  about the same time

To avoid the turn-off glitch of the output branches, the S1 switch is made larger, meaning it has smaller on-resistance than the switches of the output branches. In this way, even if all the paths are all partially on, most of the current will go through the internal path, so that the output is not affected, Fig. 4-24. On another note, the on-resistance of the output branch switches cannot be made too big, otherwise it will cause large voltage drop across the switches and limits the output swing of the CBSC block.

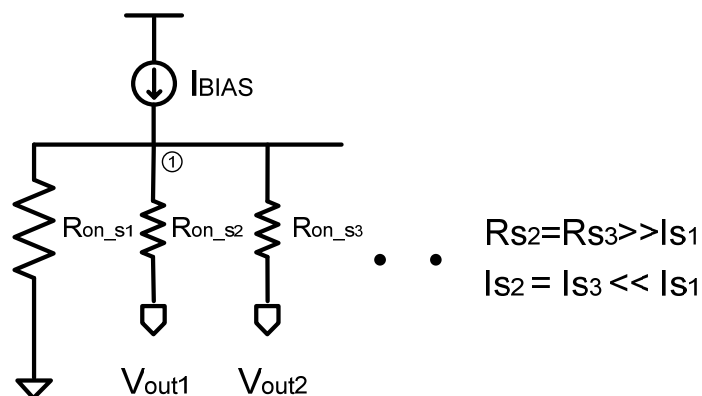


Figure 4–24: Switches are sized in a way that  $I_{s2} = I_{s3} \ll I_{s1}$  to reduce the turn-off glitch at the output

A simplified schematic of the final design of the current source for the CBSC block is shown in Fig.4-25. See Appendix B.1.6 for full schematic diagram. The current source block



receives four logic signals as input,  $E_{1p}$ ,  $E_{1n}$ ,  $E_{2p}$ ,  $E_{2n}$ , and outputs corresponding currents to the positive branch ( $V_{outp}$ ) or the negative branch ( $V_{outn}$ ). As stated earlier, when the outputs do not need any current, the currents are directed to  $V_{dd}$  or  $V_{ss}$  (ground) internally and wasted. Notice that  $V_{outp}$  and  $V_{outn}$  are mirrors of each other. When  $V_{outp}$  needs  $I_{1p}$ ,  $V_{outn}$  needs  $I_{1n}$ ; when  $V_{outp}$  needs  $I_{2p}$ ,  $V_{outn}$  needs  $I_{2n}$ , and vice versa. In another words,  $V_{outn}$  path can just use the unused branch from  $V_{outp}$  path. Then, each branch of the current source is shared between  $V_{outp}$  and  $V_{outn}$  to save current. Also,  $E_1$  and  $E_2$  will not be on at the same time. In order to not waste  $I_2$  when  $E_2$  is not on,  $I_1$  and  $I_2$  are combined together to deliver current during  $E_1$ .

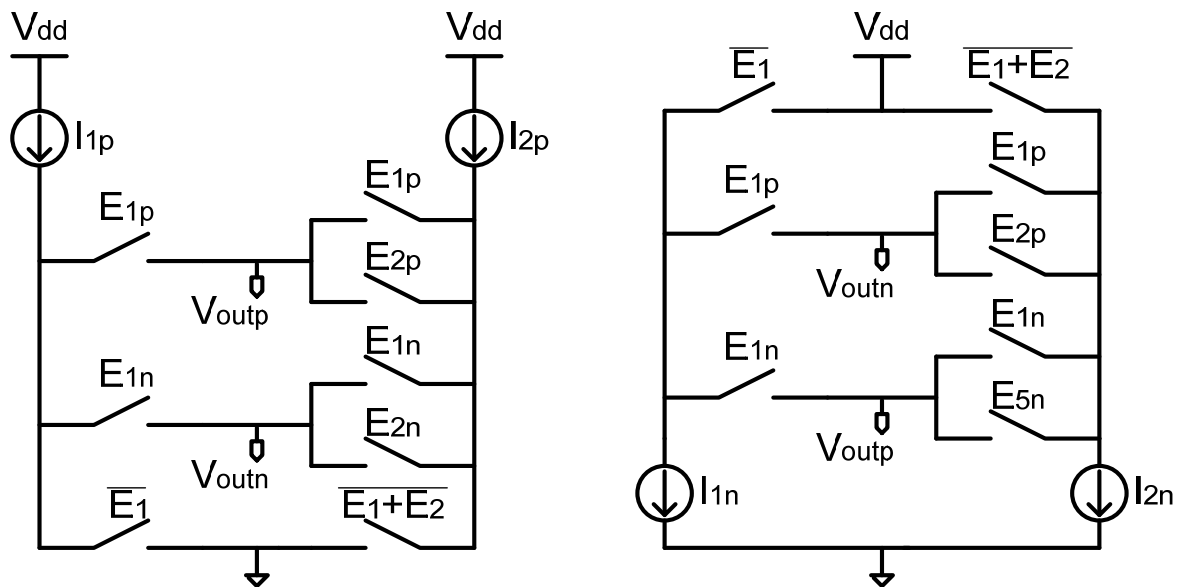


Figure 4-25: Simplified schematic of current source in CBSC block

The branches of the current source block are sized in a way that roughly  $I_{1p} = I_{1n} > I_{2p} = I_{2n}$ . How does one decide what value should  $I_1$  and  $I_2$  be? Mathematically, constant current charges capacitor in the manner described in the following equations, where  $V_{inp} - V_{inn}$  is the differential input for that cycle, and  $V_{overshoot1}$  is the overshoot voltage of a single end after E1 state.

$$(|V_{inp} - V_{inn}| + 2V_{overshoot1}) \frac{(C_{fb} + C_{in})C_{load}}{C_{fb} + C_{in} + C_{load}} = Q_1 = I_1 t_1 \quad (4.11)$$

$$2V_{overshoot1} \frac{(C_{fb} + C_{in})C_{load}}{C_{fb} + C_{in} + C_{load}} = Q_2 = I_2 t_2 \quad (4.12)$$

The goal is to find a current pair ( $I_1$  and  $I_2$ ), so that  $t_1 + t_2 <$  integration time of each cycle. A minimal  $I_2$  is desired, because the size of  $I_2$  direct affects the final overshoot voltage: the smaller  $I_2$  the smaller overshoot, and the better accuracy as a result. Ideally  $V_{overshoot1}$  should be almost constant for a particular comparator and a particular  $I_1$  value. Using the largest possible differential input for safely, one can find an estimated current pair using the above equations. It's only an estimate because there are a lot of non-idealities in real circuit design, such as comparator delay is signal dependent and does not stay constant, etc. Minor tweaks are necessary for optimal performance.

## 4.9 Prototype CBSC 2<sup>nd</sup> Order $\Delta\Sigma$ Modulator

With the updated 2<sup>nd</sup> order  $\Delta\Sigma$  modulator architecture, CBSC integrators, and *qtzr* from the original op-amp design, a prototype CBSC 2<sup>nd</sup> order  $\Delta\Sigma$  modulator is implemented using TSMC .18  $\mu m$  technology. The digital gates used in the logic blocks are behavior model, so that the parameters are easy to change for the simulation. The top level schematic is demonstrated in Fig. 4-26. Please refer to chapter 5 for simulation results and comparison against the op-amp based modulator.

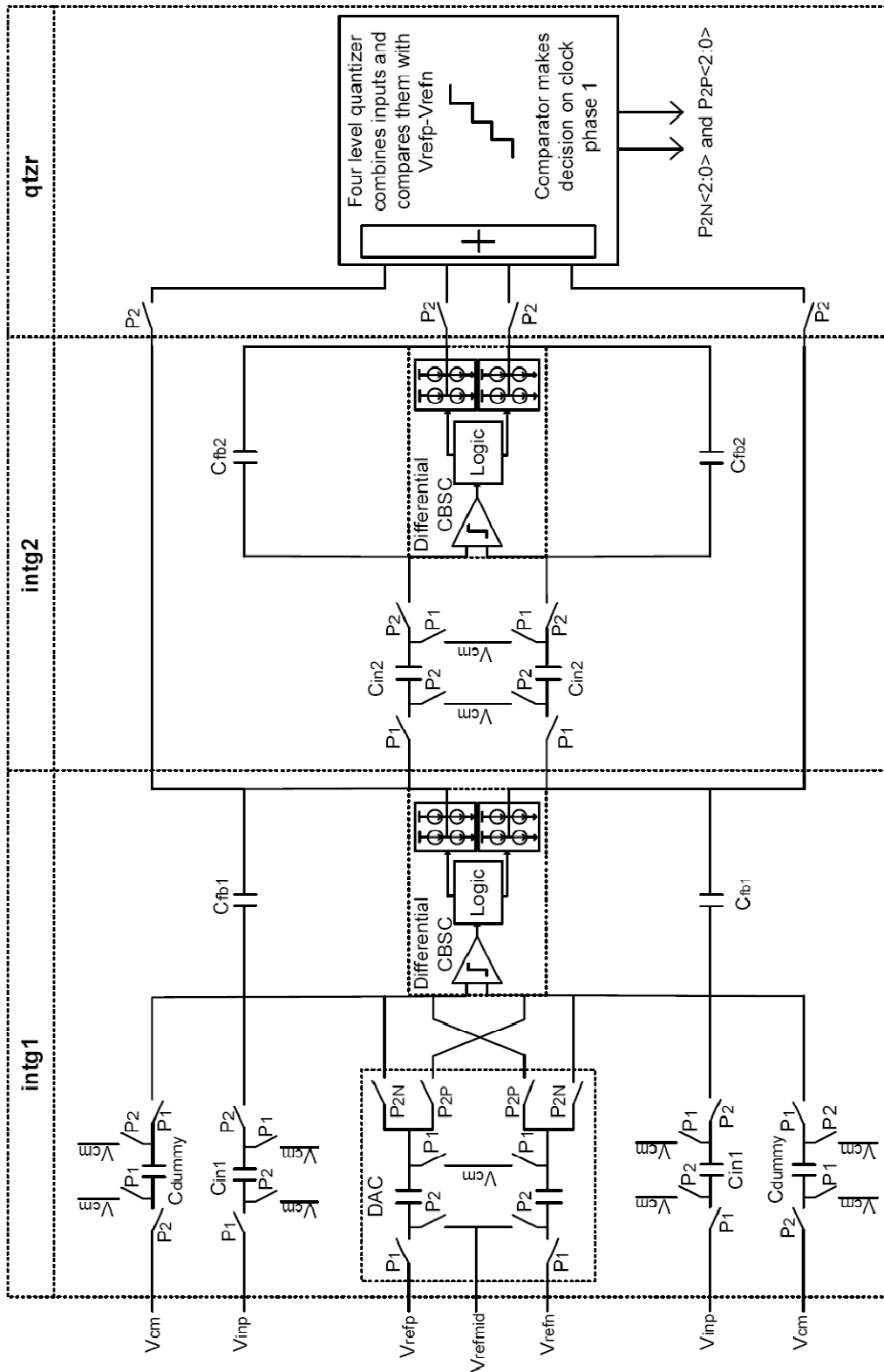


Figure 4–26: Top level schematics of a CBSC 2<sup>nd</sup> order  $\Delta\Sigma$  modulator

# Chapter 5

## Simulation Result

### 5.1 SNR

Cadence is used to simulate different versions of the modulator. The setup is in Table 5-1.

Matlab then is used to process the sum of *qtzr* output data and create spectrums for comparison, Fig. 5-1. The resulting SNR for each version is listed in Table 5-2.

The CBSC based ideal circuit version has a 30 dB drop from the mathematically calculated noise-free result, while the op-amp based ideal circuit version can perform almost perfectly. The reason for the performance difference is that for the ideal circuit, the op-amp gain can be set very large and achieve almost no error. However, the logic for CBSC version is generated using several stages of digital gates. Even though digital gates are generally very fast, long enough delay is accumulated after several stages. As a result, overshoot error is unavoidable, which decreases the accuracy.

The accuracy of the CBSC  $\Delta\Sigma$  modulator is further decreased from the ideal version to the transistor level design. The main error comes from the comparator overshoot error and delay. The glitch caused by the on-resistance of the switch is also a factor. More careful design is necessary to push the performance of this transistor level design.

Table 5–1: Simulation setups

$F_{in}$	Input frequency	4 kHz
$F_s$	Sampling frequency	10 MHz
$T$	Sampling period	100 nS
$T_{CLK}$	Clock $P_1$ and $P_2$ width	47.3 nS
$V_{in}$	Differential input voltage amplitude	1 rmsV
$V_{dd}$	Top rail power supply voltage	2 V
$V_{cm}$	Common mode voltage	1 V
$V_{ss}$	Ground	0 V
$t_{raise}$	Raise time of the digital gates and clocks	100 ps
$t_{fall}$	Fall time of the digital gates and clocks	100 ps
$I_{intg1\_E1}$	The coarse charge current of integrater-1	129 $\mu$ A
$I_{intg1\_E2}$	The fine charge current of integrater-1	21.5 $\mu$ A
$I_{intg2\_E1}$	The coarse charge current of integrater-2	32.9 $\mu$ A
$I_{intg1\_E2}$	The fine charge current of integrater-2	4.7 $\mu$ A
OSR	Over sampling ratio	250

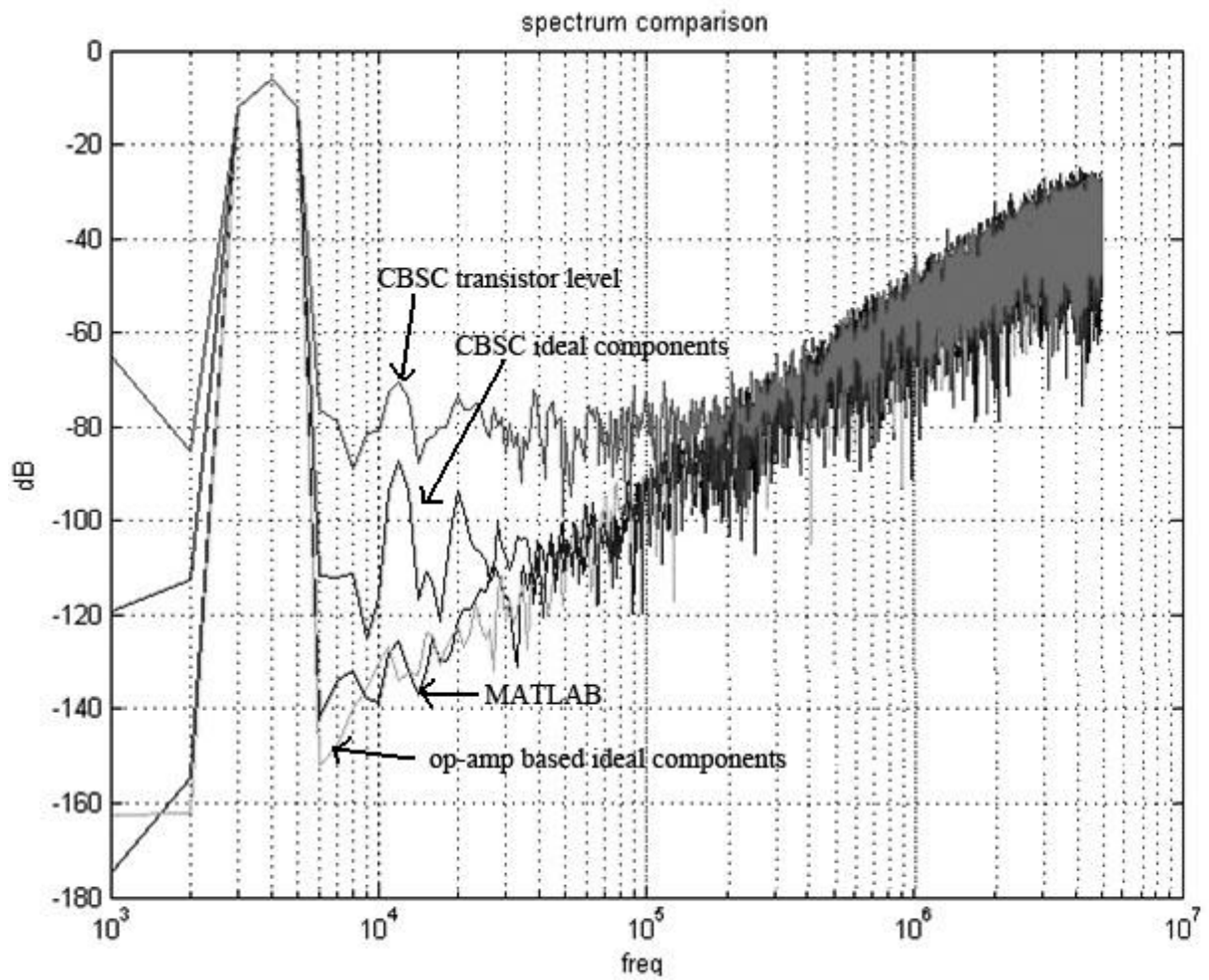


Figure 5–1: Spectrum comparison of different versions of  $\Delta\Sigma$  modulator

Table 5–2: resulting SNR from different versions

Version	SNR (dB)
Matlab (without noise)	114.20
Op-amp based Ideal version	112.89
Op-amp based real transistor version	~ 90
CBSC based ideal version	81.14
CBSC real transistor version	60.57

## 5.2 Power Usage

Despite the lower accuracy, the CBSC  $\Delta\Sigma$  modulator shows a big advantage in power saving over the op-amp based design. Table 5-2 is a comparison of the power usage and performance of the two designs. The power usage of  $qtzr$  is not listed, because  $qtzr$  from the original op-amp version is used for the CBSC modulator. If we use ENOB over power usage as a figure of merit to compare the two versions, CBSC modulator shows its advantage. In this project, the CBSC modulator is a trial version. There is lots of room for improvements. The performance should be able to be pushed closer to ideal and achieve close to 80 dB SNR.

Table 5–3: Current usage comparison

		Op-amp based	CBSC based	
Current Usage	Intg1	700 $\mu A$	Current source	330.5 $\mu A$
			Comparator	33.5 $\mu A$
	Intg2	150 $\mu A$	Current source	107.8 $\mu A$
			Comparator	28.5 $\mu A$
Total	850 $\mu A$	438.3 $\mu A$		
ENOB		16 bit	9.7 bit	
FOM = ENOB/Power		9.41 bit/nW	11.065 bit/nW	

## Chapter 6

### Conclusion

A new comparator-based switched-capacitor 2<sup>nd</sup> order  $\Delta\Sigma$  modulator is presented. This CBSC modulator has a number of advantages compared to the original op-amp based design.

As demonstrated in chapter 5, the CBSC modulator consumes much less power, but has yet to match the performance of the op-amp based design. It is appropriate in applications that have very tight power requirement but not very strict accuracy. One may argue that power and accuracy are always a trade-off: if targeting lower accuracy, an op-amp can use less power also. However, there is a limit. When the current is lower than a certain limit, op-amps will not settle at all. For example, the original modulator would not be able to operate at the power level of this CBSC modulator. Also, CBSC methodology is more amenable to design in scaled technology. Instead of forcing the virtual ground, CBSC design detects the equal condition in an open-loop manner, so it does not have stability issues as op-amps. Finally, CBSC is compatible with most known architectures, with minor change.

One issue of CBSC design is discussed in *section 4.2*: CBSC designs can only drive switched-capacitor loads. CBSC design cannot drive another stage directly. For those designs that have a direct driving stage, architectural adoption is needed.



# Chapter 7

## Future Work and Ideas

Some suggestion and ideas for future work:

- An optimized design (shorter delay and low offset voltage) of the comparator in CBSC will help increase the accuracy.
- Overshoot cancellation technique in [4] may shorten the integration time or increase accuracy, because a smaller fine charge current can be used.
- To further save power, the current source and comparator can be turned off while they are not being used (in *idle state*). However, in order to avoid possible harmful turn-on transient behaviors, an advanced clock may need to be used to turn them on a little bit before their outputs are supposed to be used.
- The smaller the capacitors used in the integrators the smaller the charging currents. To further save power, one may use smaller capacitors. But be careful with the leakage currents.
- Noise, non-ideality, and non-linearity analysis

# Appendix A

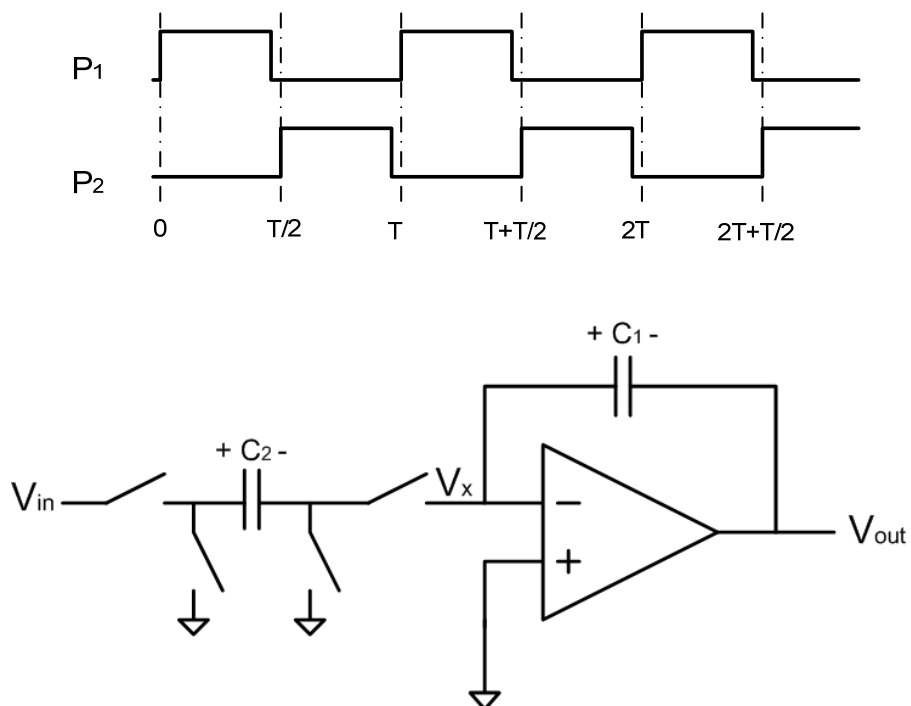
## Calculations

This appendix provides some mathematical proofs to the functionalities of CBSC circuits discussed in this paper. The comparison between the CBSC circuits and the traditional op-amp based circuits are demonstrated also.

### A.1 Op-Amp Based Integrator

Mathematical derivation of the z-transform of an op-amp based integrator is demonstrated in this section.

Clock: Here  $P_1$  is the sampling phase, and  $P_2$  is the integration phase.



Ideal Op-Amp:  $V_- = V_+ = 0$  virtual ground.

At  $t = nT$ :

$$Q_1(nT) = V_1(nT)C_2$$

$$Q_1\left(nT + \frac{T}{2}\right) = V_1\left(nT + \frac{T}{2}\right)C_2 = 0$$

At  $t = nT + \frac{T}{2}$ :

$$Q_1\left(nT + \frac{T}{2}\right) = V_1\left(nT + \frac{T}{2}\right)C_2 = 0$$

$$Q_2\left(nT + \frac{T}{2}\right) = V_2\left(nT + \frac{T}{2}\right)C_1$$

At  $t = nT + T$ :

$$Q_1(nT + T) = V_1(nT + T)C_2$$

$$Q_2(nT + T) = V_2(nT + T)C_1 - V_2\left(nT + \frac{T}{2}\right)C_1$$

Combine the above results:

$$-Q_1(nT) + Q_2(nT) = -Q_1\left(nT + \frac{T}{2}\right) + Q_2\left(nT + \frac{T}{2}\right)$$

$$V_2\left(nT + \frac{T}{2}\right)C_1 = -V_1(nT)C_2 + V_2(nT)C_1$$

$$V_2(nT + T)C_1 = V_2(nT)C_1 = -V_1(nT)C_2$$

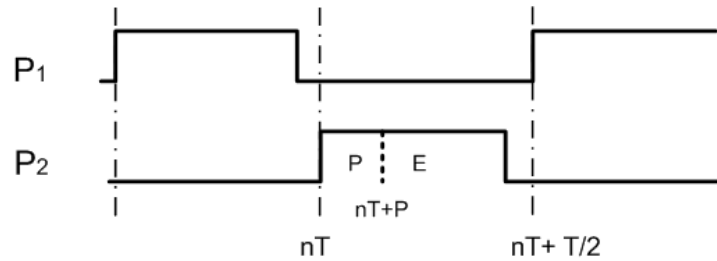
Z-transform:

$$(Z - 1)C_1V_2 = -V_1C_2$$

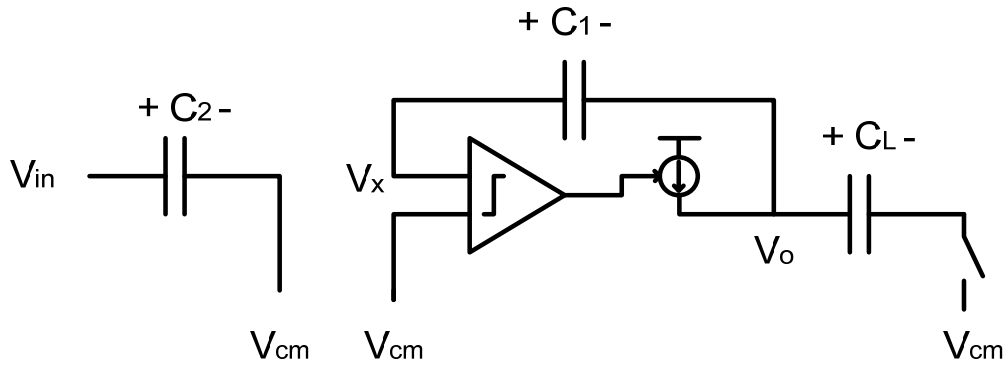
$$\frac{V_2}{V_1} = -\frac{C_2}{C_1} \frac{z^{-1}}{(1 - z^{-1})}$$

## A.2 CBSC Integrator with preset phase

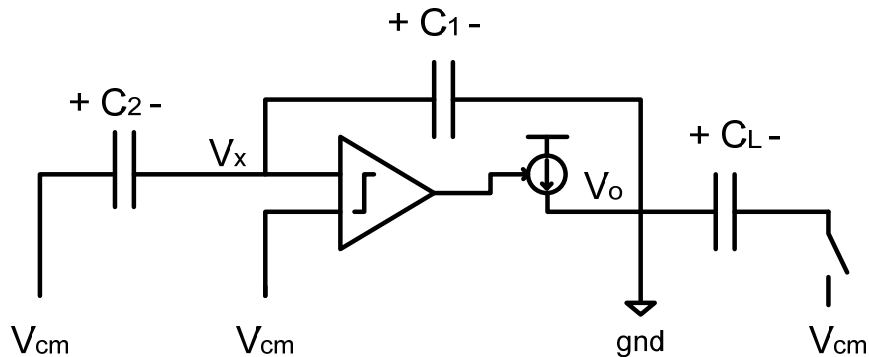
Mathematical derivation of the z-transform of a CBSC based integrator with preset phase is demonstrated in this section. This is the original configuration introduced in [4].



1) During  $P_1$ :



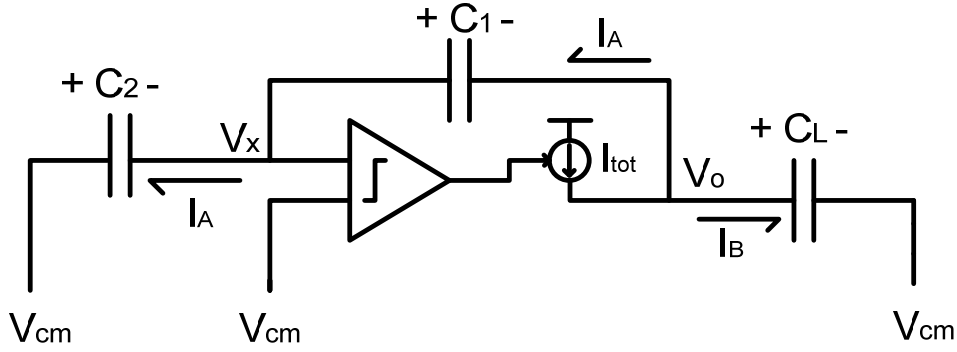
2) During preset (P) in  $P_2$ :  $V_o[n+p] = 0$  (demonstrated as grounded, but it should be connected to the lowest voltage possible)



Charge Balance:

$$\begin{aligned}
C_2 V_{2final} - C_1 V_{1final} &= C_2 V_{2initial} - C_1 V_{1initial} \\
C_2 (V_{cm} - V_x(nT + P)) - C_1 (V_x(nT + P)(nT + P) - V_o(nT + P)) \\
&= C_2 (V_{in}(nT) - V_{cm}) - C_1 (V_{cm} - V_o(nT)) \\
(C_1 + C_2) V_x(nT + P) &= -C_2 V_{in}(nT) - C_1 V_o(nT) + (C_1 + 2C_2) V_{cm}
\end{aligned}$$

3) During charge transfer (E) in  $P_2$ :  $I_{tot} = I_A + I_B$



$$Q_2 \left( nT + \frac{T}{2} \right) = Q_2(nT + P) - I_o t = 0$$

Same amount of charge goes through  $C_1$ :

$$\begin{aligned}
Q_1 \left( nT + \frac{T}{2} \right) &= Q_1(nT + P) - I_o t \\
&= Q_1(nT + P) - Q_2(nT + P) \\
&= V_x(nT + P) C_1 - V_{cm} C_2 + V_x(nT + P) C_2 \\
&= (C_1 + C_2) V_x(nT + P) - V_{cm} C_2
\end{aligned}$$

$$\begin{aligned}
\text{Also } Q_1 \left( nT + \frac{T}{2} \right) &= \left( V_{cm} - V_o \left( nT + \frac{T}{2} \right) \right) C_1 \\
&= (V_{cm} - V_o(nT + T)) C_1
\end{aligned}$$

From the above we get

$$-V_o(nT + T) C_1 = -C_2 V_{in}(nT) - C_1 V_o(nT) + C_2 V_{cm}$$

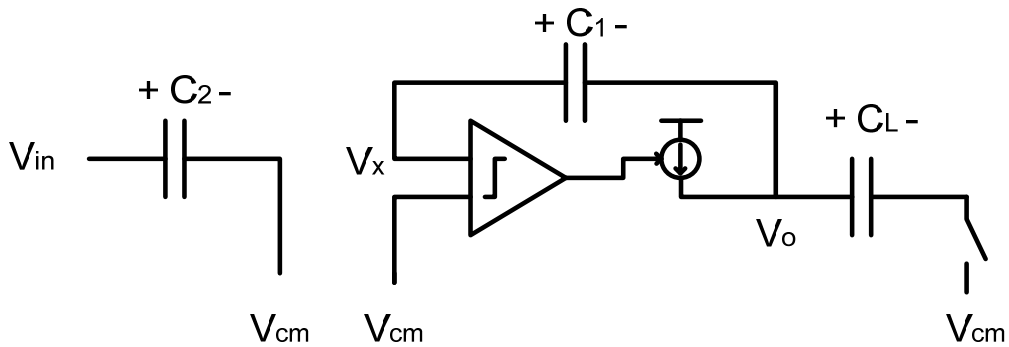
$$\frac{V_o}{V_{in} - V_{cm}} = \frac{C_2}{C_1} \frac{z^{-1}}{1 - z^{-1}}$$

Same form as the op-amp based integrator.

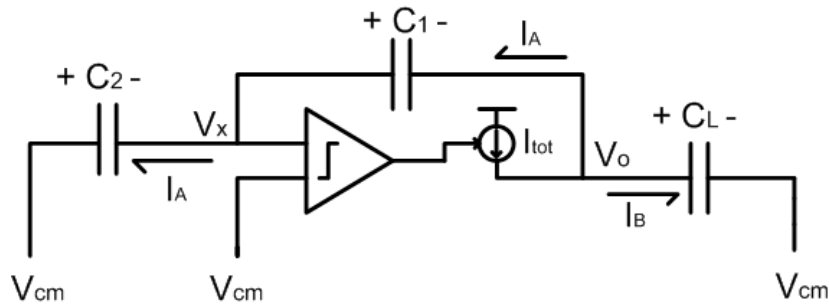
### A.3 Proposed CBSC Integrator without Preset Phase

Mathematical derivation of the z-transform of a CBSC based integrator without preset phase is demonstrated in this section. This is the configuration designed base on the original one in [4], and is proposed for the CBSC 2<sup>nd</sup> order  $\Delta\Sigma$  modulator discussed in this paper.

During P1:



During P2:



$$1) \quad V_x(nT) = V_o(nT) + \frac{Q_{C_1}(nT)}{C_1} = V_{cm}$$

$$V_o(nT) = V_{cm} - \frac{Q_{C_1}(nT)}{C_1}$$

$$I_o t = -C_2 V_{in}$$

$$2) \quad Q_{C_1} \left( nT + \frac{T}{2} \right) = Q_{C_1}(nT) + I_o t = Q_{C_1}(nT) - C_2 V_{in}$$

$$V_x \left( nT + \frac{T}{2} \right) = V_o(nT + T) + \frac{Q_{C_1}(nT) - C_2 V_{in}}{C_1} = V_{cm}$$

$$V_o(nT + T) = V_{cm} - \frac{Q_{C_1}(nT) - C_2 V_{in}}{C_1}$$

Combine the above:

$$V_o(nT + T) - V_o(nT) = \frac{C_2}{C_1} V_{in}$$

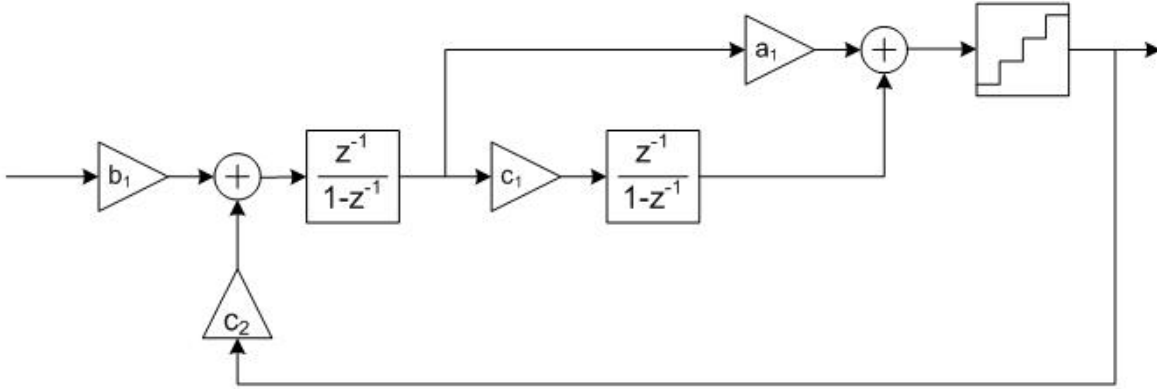
$$\frac{V_o}{V_{in}} = \frac{C_2}{C_1} \frac{z^{-1}}{1 - z^{-1}}$$

Same result with the one with preset



## A.4 DC Gain of the 2<sup>nd</sup> Order $\Delta\Sigma$ Modulator

Below is the block diagram of the 2<sup>nd</sup> order  $\Delta\Sigma$  modulator built in this paper. This section provides the mathematical calculation of its overall DC gain.



Coefficients are:  $a_1 = 1$ ;  $b_1 = \frac{1}{3}$ ;  $c_1 = -\frac{2}{3}$ ;  $c_2 = \frac{1}{2}$ , with build in gain of 3 in *qtzr*.

Use Mason's rule to find the gain without  $b_1$ :

The forward paths and gains ( $M_j$ ):

$$M_1 = \frac{1}{2} \left( \frac{z^{-1}}{1-z^{-1}} \right)^2$$

$$M_2 = \frac{z^{-1}}{1-z^{-1}}$$

The loops and their gains:

$$Loop1 = -\frac{1}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)^2$$

$$Loop2 = -\frac{2}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)$$

$\Delta_j$ : 1 – the loops remaining after removing path  $j$ . If none remain, then  $\Delta_j = 1$ .

$\Delta_1 = 1$  and  $\Delta_2 = 1$

$\Delta$ : 1 -  $\Sigma$  loop gains +  $\Sigma$  non-touching loop gains taken two at a time -  $\Sigma$  non-touching loop gains taken three at a time +  $\Sigma$  non-touching loop gains taken four at a time

$$\Delta = 1 + \frac{1}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)^2 + \frac{2}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)$$

$M(Z)$  total gain

$$M(Z) = \frac{\sum_j M_j \Delta_j}{\Delta} (Z) = \frac{\frac{1}{2} \left( \frac{z^{-1}}{1-z^{-1}} \right)^2 + \left( \frac{z^{-1}}{1-z^{-1}} \right)}{1 + \frac{1}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)^2 + \frac{2}{3} \left( \frac{z^{-1}}{1-z^{-1}} \right)}$$

For DC gain  $Z = 1$ :

$$M(1) = \frac{\frac{1}{2}}{\frac{1}{3}} = \frac{3}{2}$$

Overall gain:

$$M_{\Delta\Sigma} = b_1 M(1) = \frac{1}{3} * \frac{3}{2} = \frac{1}{2}$$

## A.5 Comparator Offset Model

### CBSC Comparator Offset

Same results as A.2 before phase E. During E in phase 2, the current source is shut off when  $V_x = V_{cm} + V_{offset}$  instead of  $V_x = V_{cm}$ .

$$1) \quad Q_2\left(nT + \frac{T}{2}\right) = Q_2(nT + P) - I_A t = (V_{cm} - (V_{cm} + V_{offset}))C_2$$

$$I_A t = (V_{cm} - V_x(nT + P) + V_{offset})C_2$$

$$2) \quad Q_1\left(nT + \frac{T}{2}\right) = Q_1(nT + P) - I_A t$$

$$= V_x(nT + P)C_1 - (V_{cm} - V_x(nT + P) + V_{offset})C_2$$

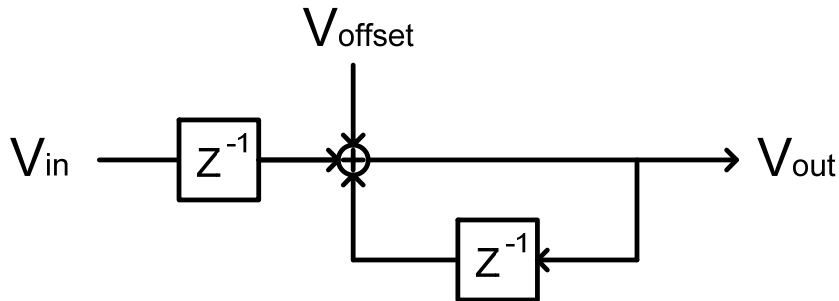
$$3) \quad Q_1\left(nT + \frac{T}{2}\right) = Q_1(nT + T) = (V_{cm} + V_{offset} - V_o(nT + T))C_1$$

$$V_x(nT + P)(C_1 + C_2) - (V_{cm} + V_{offset})(C_1 + C_2) + V_o(nT + T)C_1 = 0$$

Rearrange

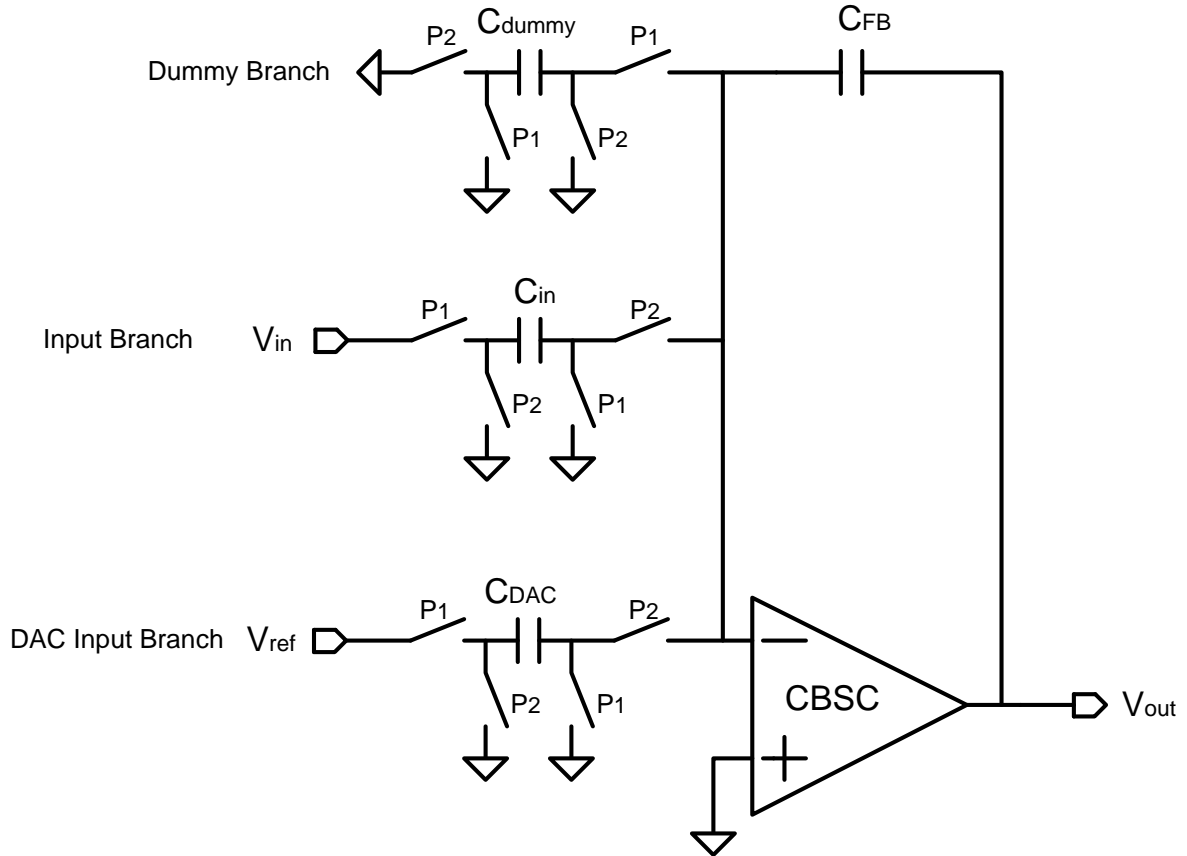
$$V_o(nT + T) = \frac{C_2}{C_1}(V_{in}(nT) - V_{cm}) + V_o(nT) + \frac{C_1 + C_2}{C_1}V_{offset}$$

The above equation shows that in the  $\Delta\Sigma$  loop, the comparator offset voltage can be modeled as:



## A.6 Calculation of modulator thermal noise

This section provides a mathematical calculation of the thermal noise of a differential integrator used in the CBSC 2<sup>nd</sup> order  $\Delta\Sigma$  modulator.



The above figure demonstrates a single ended *intg1* with three branches: (1) input, (2) DAC, (3) and dummy branch. The input referred thermal noise (KT/C noise) can be calculated as follows.

$$\text{For (1)} \quad n_1^2 = \frac{KT}{C_{in}}$$

$$\text{For (2)} \quad n_2^2 = \frac{KT}{C_{DAC}} \left( \frac{C_{DAC}^2}{C_{FB}^2} \right) \left( \frac{C_{FB}^2}{C_{in}^2} \right) = KT \frac{C_{DAC}}{C_{in}^2}$$

$$\text{For (3)} \quad n_3^2 = \frac{KT}{C_{dummy}} \left( \frac{C_{dummy}^2}{C_{FB}^2} \right) \left( \frac{C_{FB}^2}{C_{in}^2} \right) = KT \frac{C_{dummy}}{C_{in}^2}$$

Total thermal noise for single ended modulator (one phase )

$$\begin{aligned}n_{single\_ended}^2 &= n_1^2 + n_2^2 + n_3^2 \\ &= KT \frac{1}{C_{in}} + KT \frac{C_{DAC}}{C_{in}^2} + KT \frac{C_{dummy}}{C_{in}^2} \\ &= \frac{KT}{C_{in}} \left( 1 + \frac{C_{DAC}}{C_{in}} + \frac{C_{dummy}}{C_{in}} \right)\end{aligned}$$

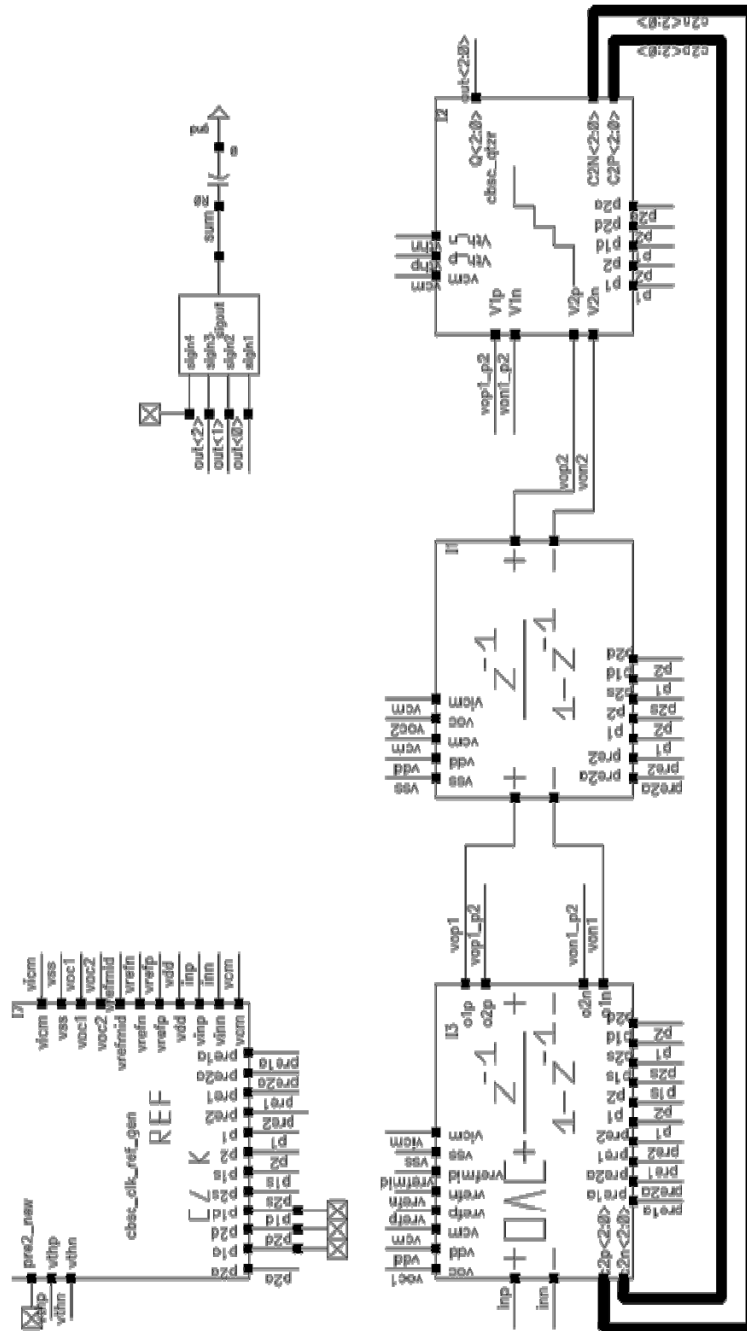
Total thermal noise for fully differential modulator (both phases)

$$\begin{aligned}n_{differential}^2 &= n_{single\_ended}^2 \times 2 \times 2 \\ &= \frac{4KT}{C_{in}} \left( 1 + \frac{C_{DAC}}{C_{in}} + \frac{C_{dummy}}{C_{in}} \right)\end{aligned}$$

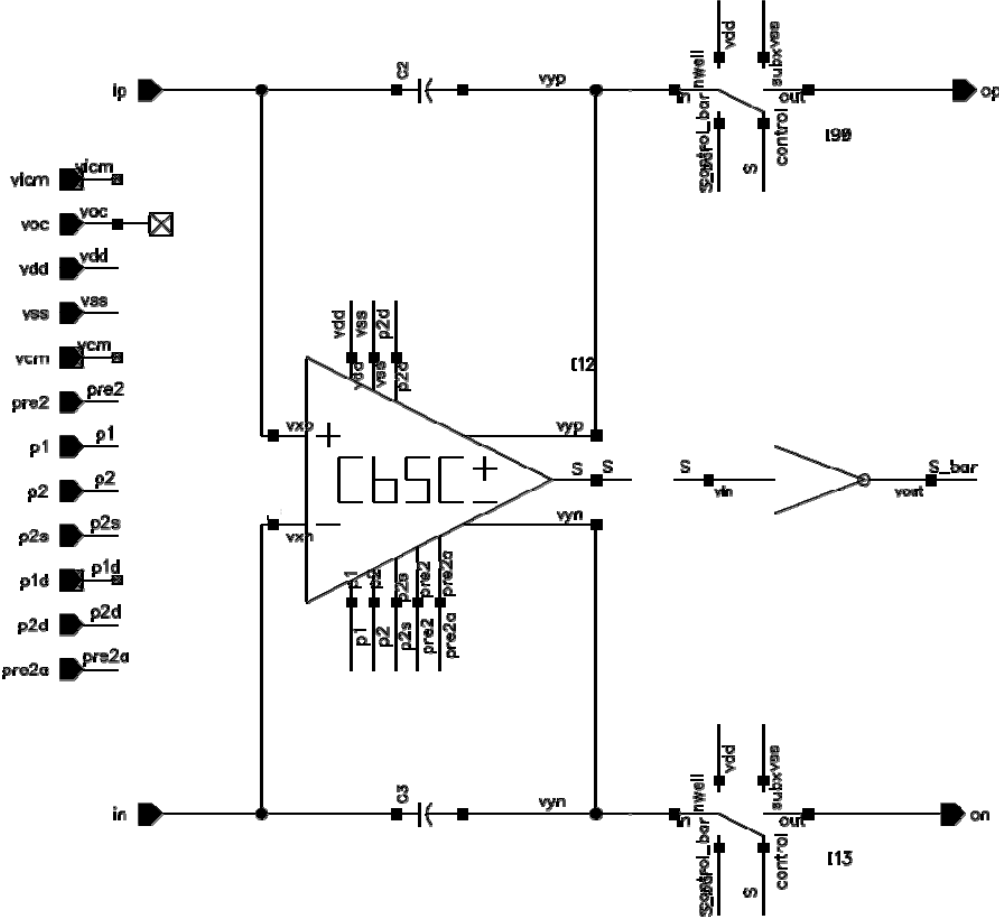
# Appendix B Schematics

This appendix shows the schematics of the 2<sup>nd</sup> order  $\Delta\Sigma$  modulator designed in this paper.

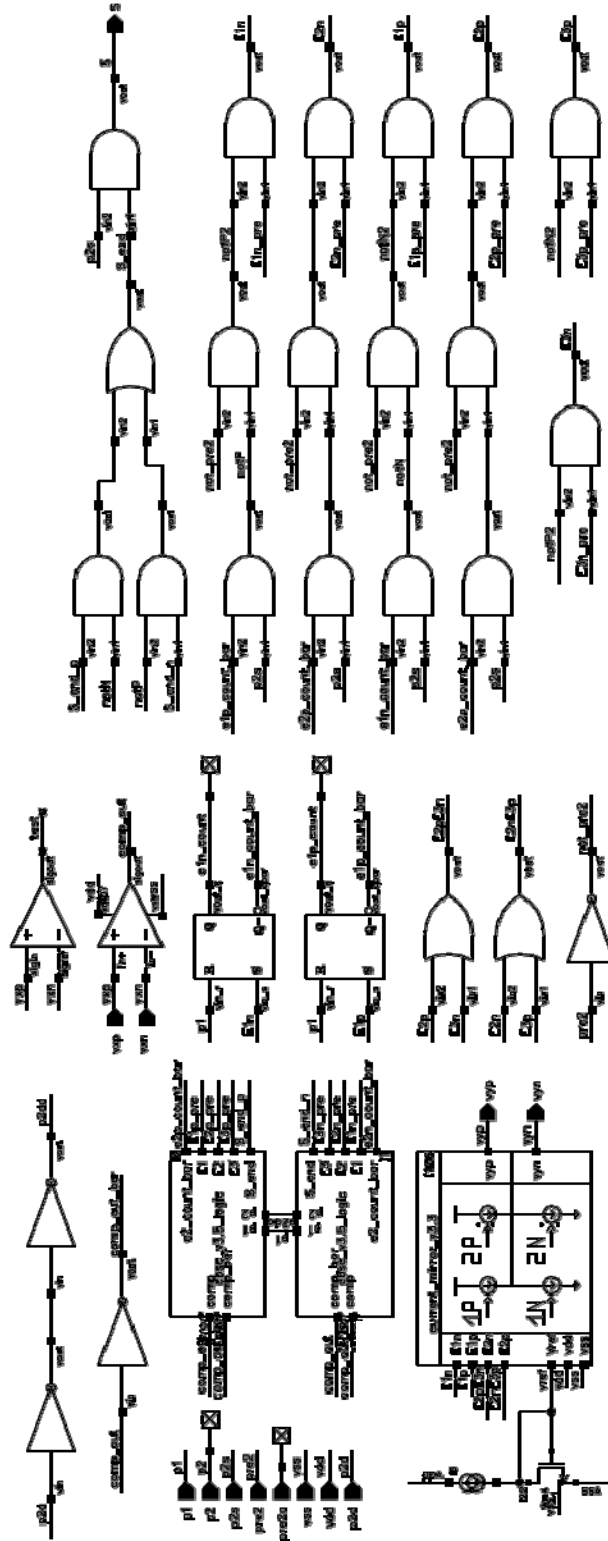
## B.1 Top Level



### B.2 *Intg2* (sampling stage is included in *intg1*)

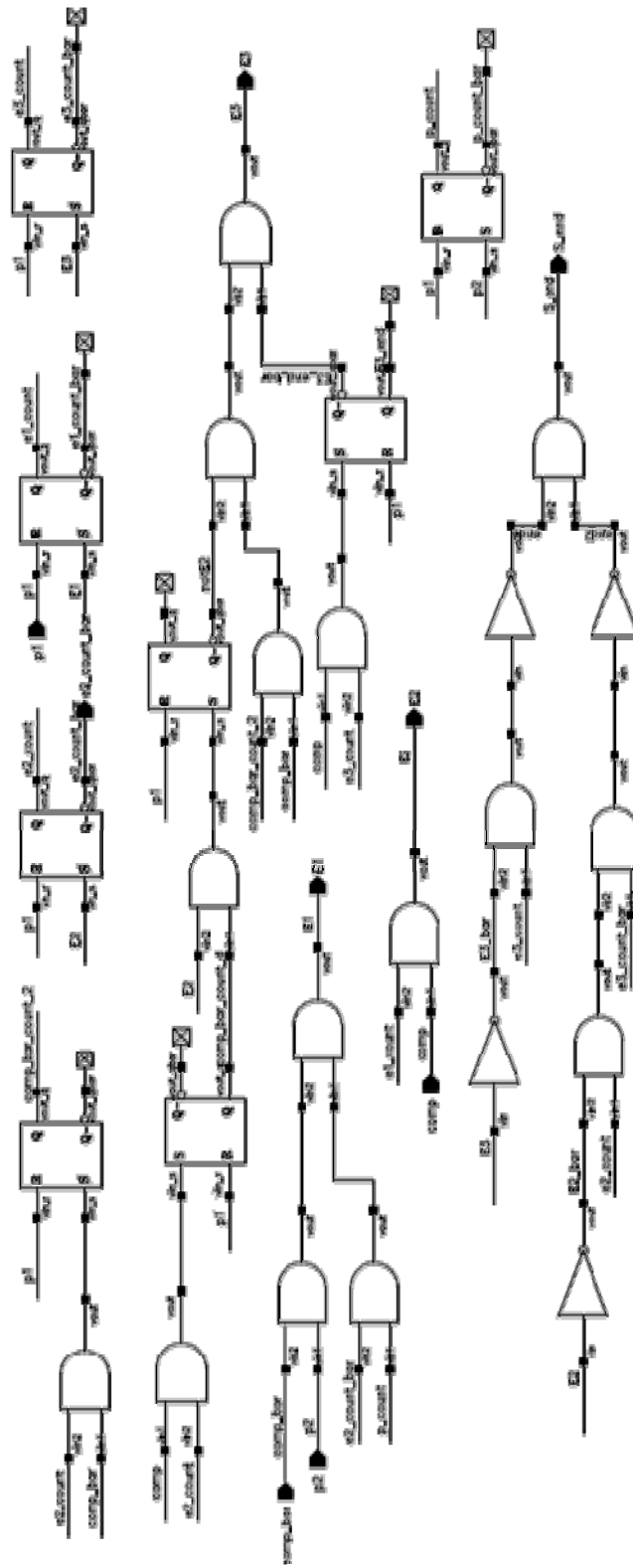


### B.3 CBSC without Dummy Branch

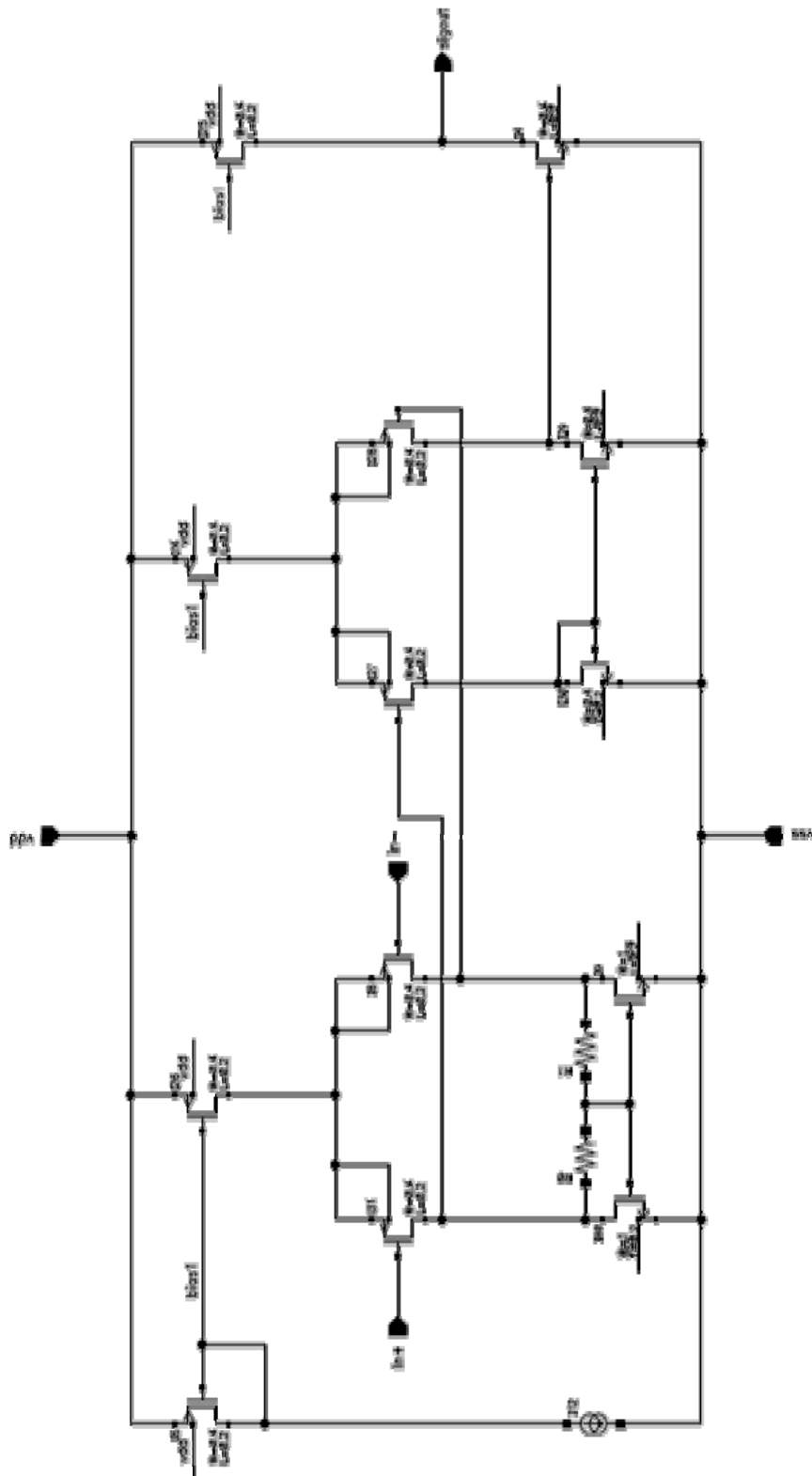




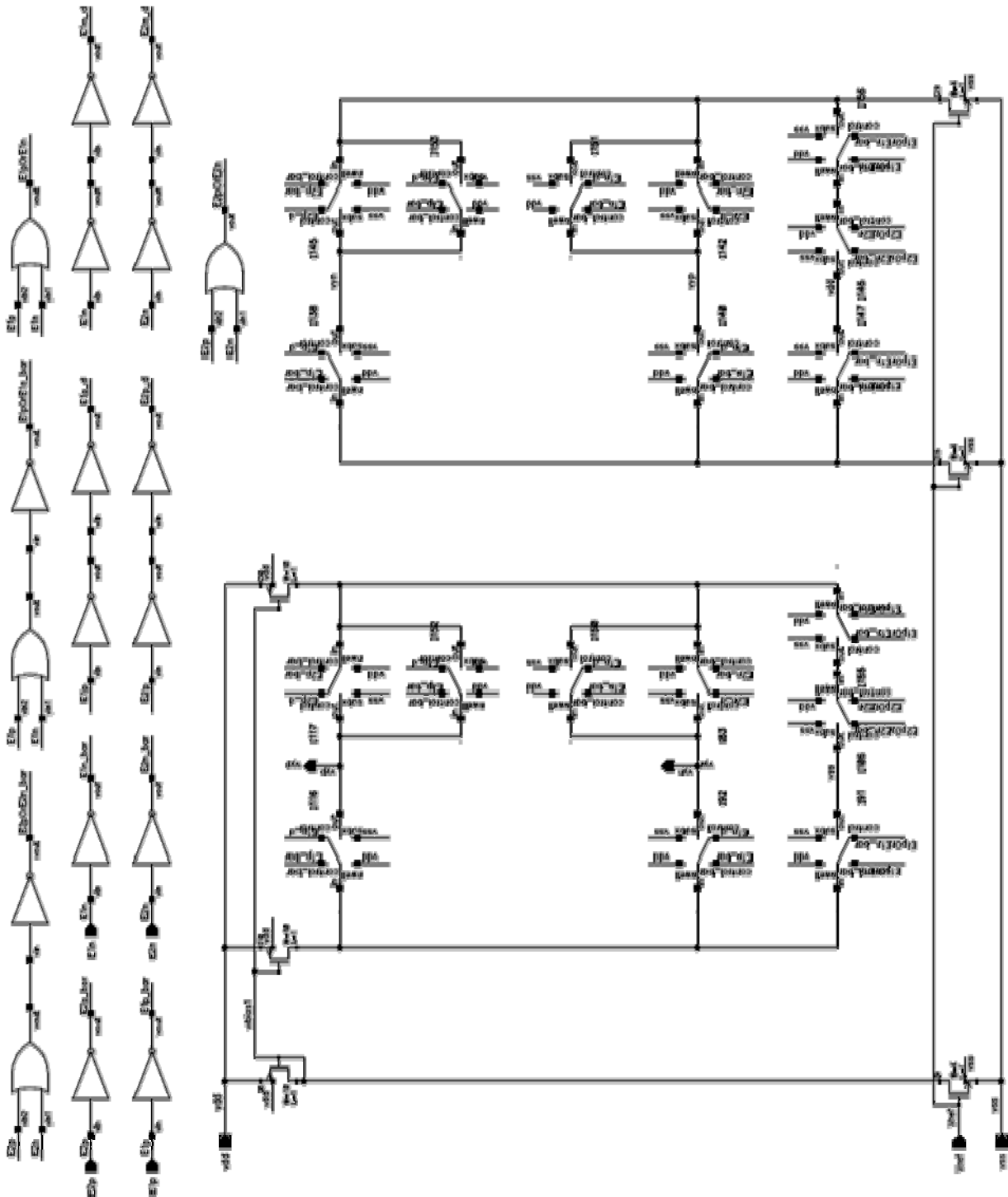
## B.4 Logic of CBSC without Dummy Branch



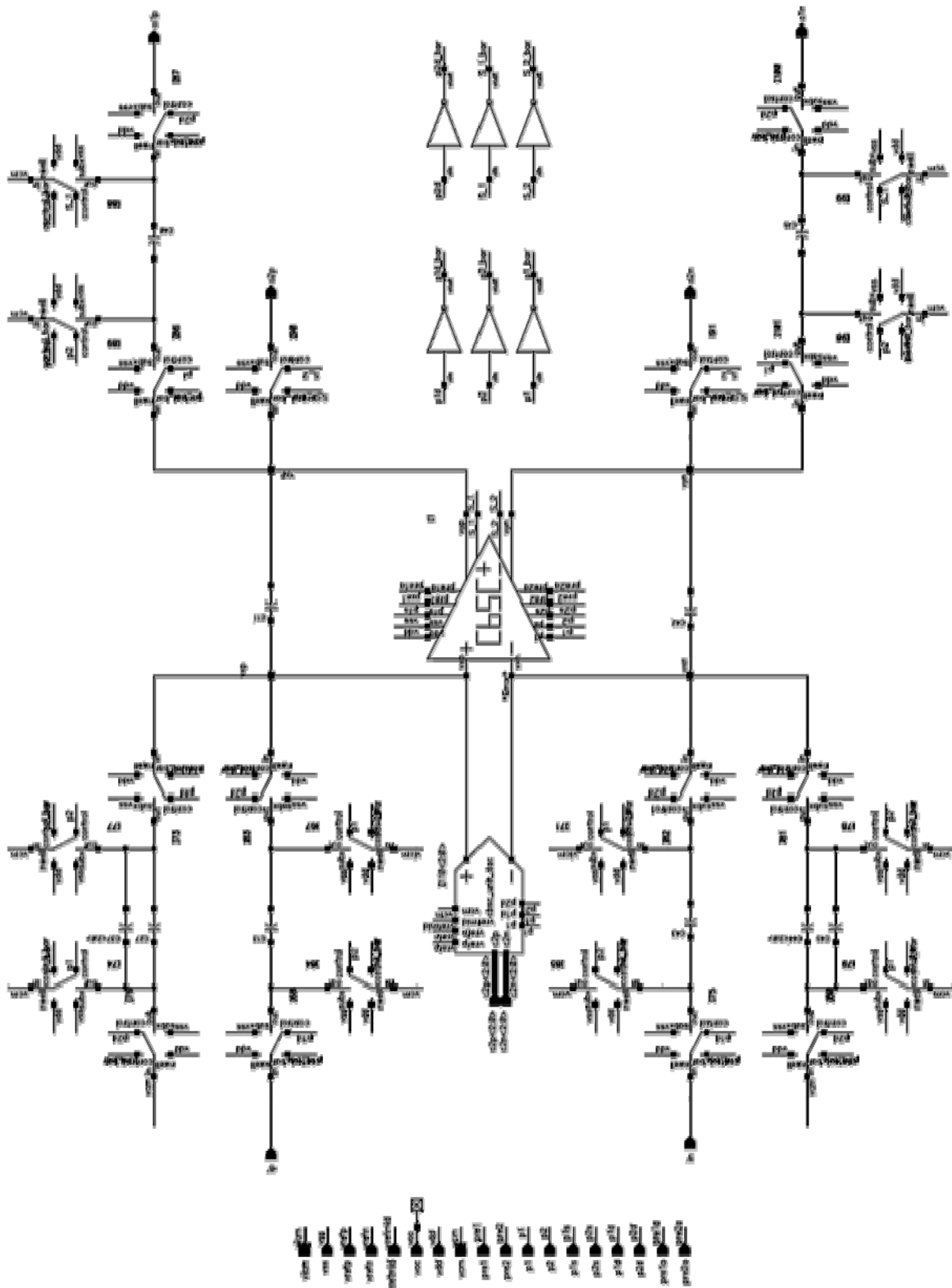
## B.5 Comparator in CBSC



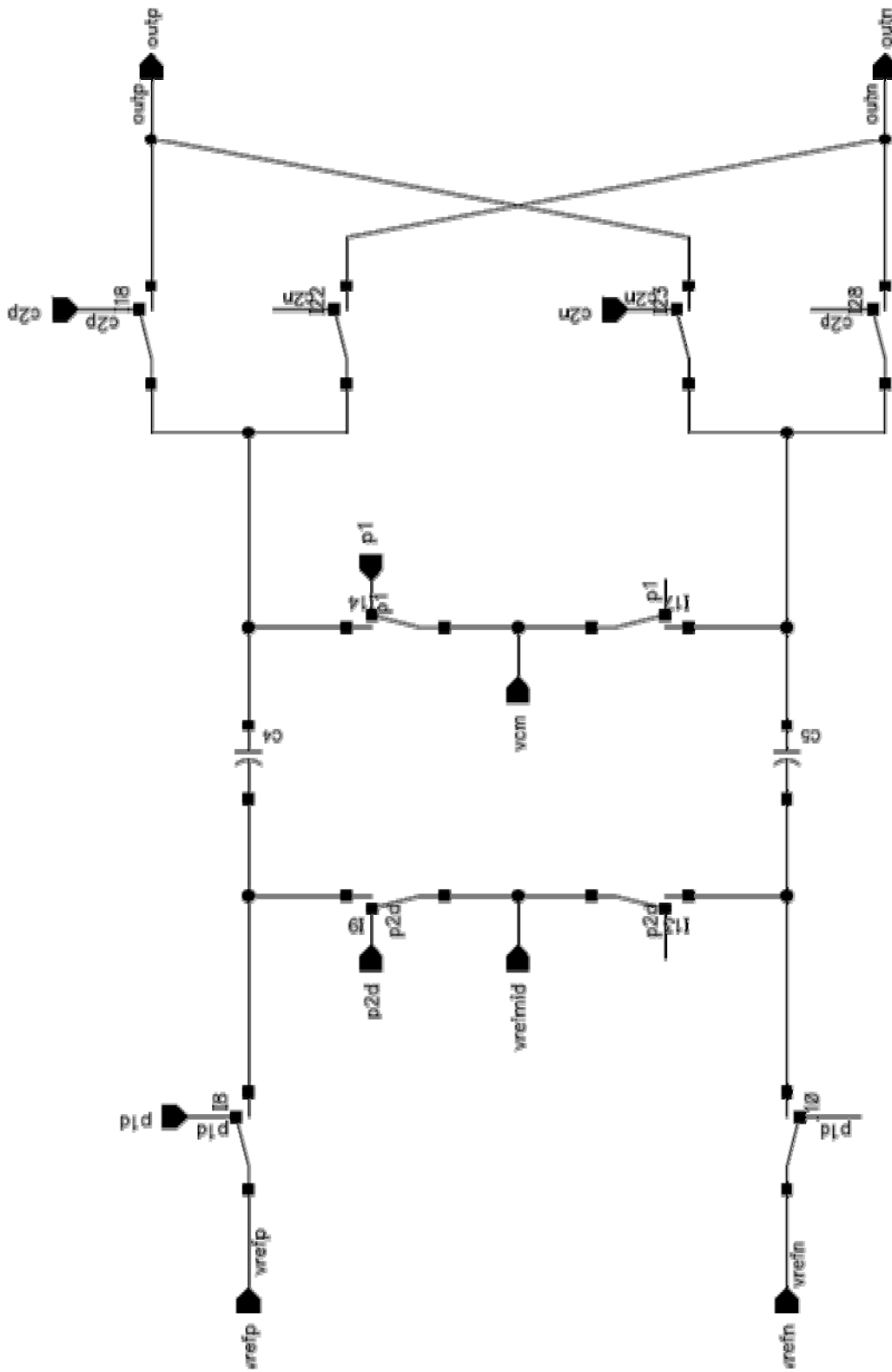
## B.6 Current Source in CBSC



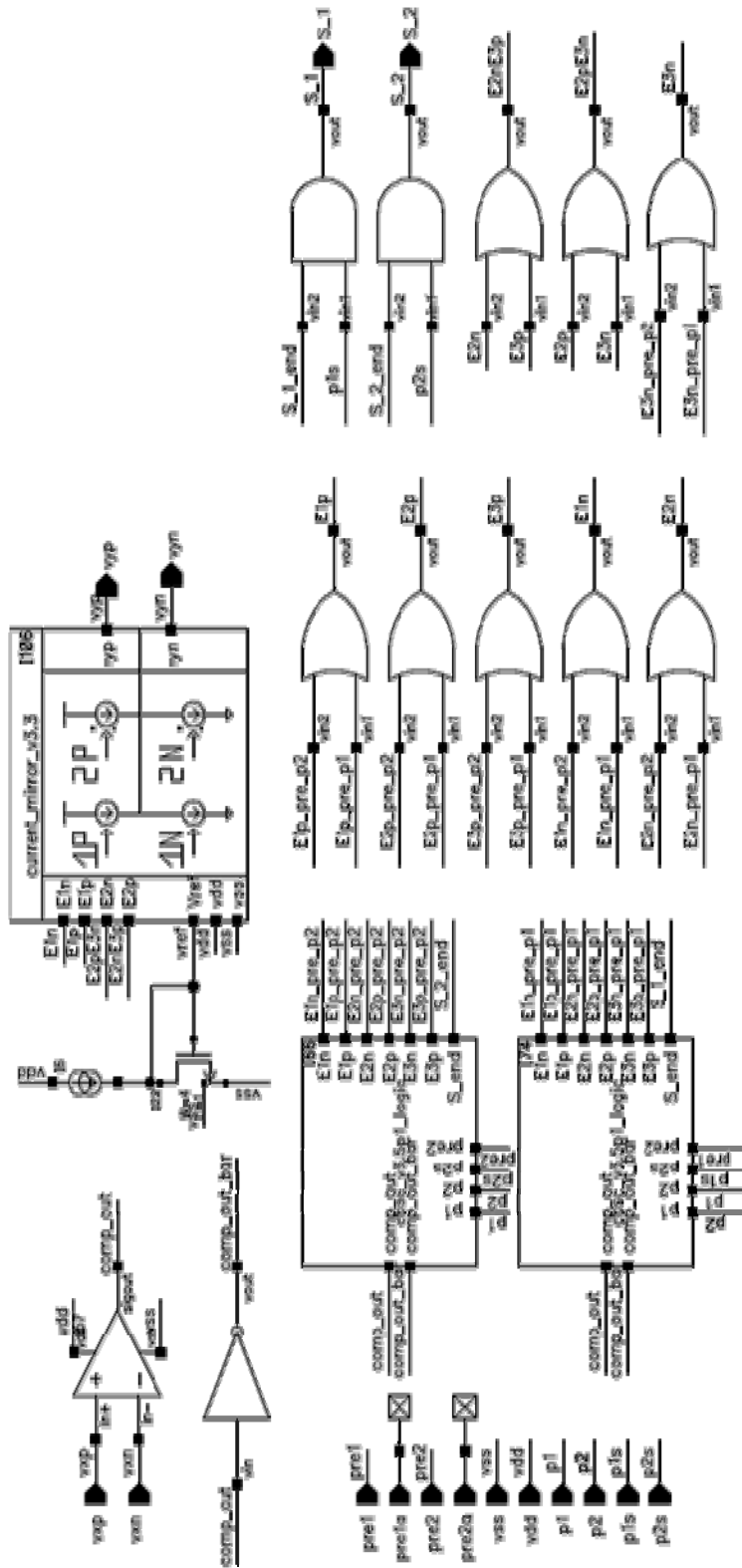
## B.7 *Intg1* (Including sampling stage of *intg2*)



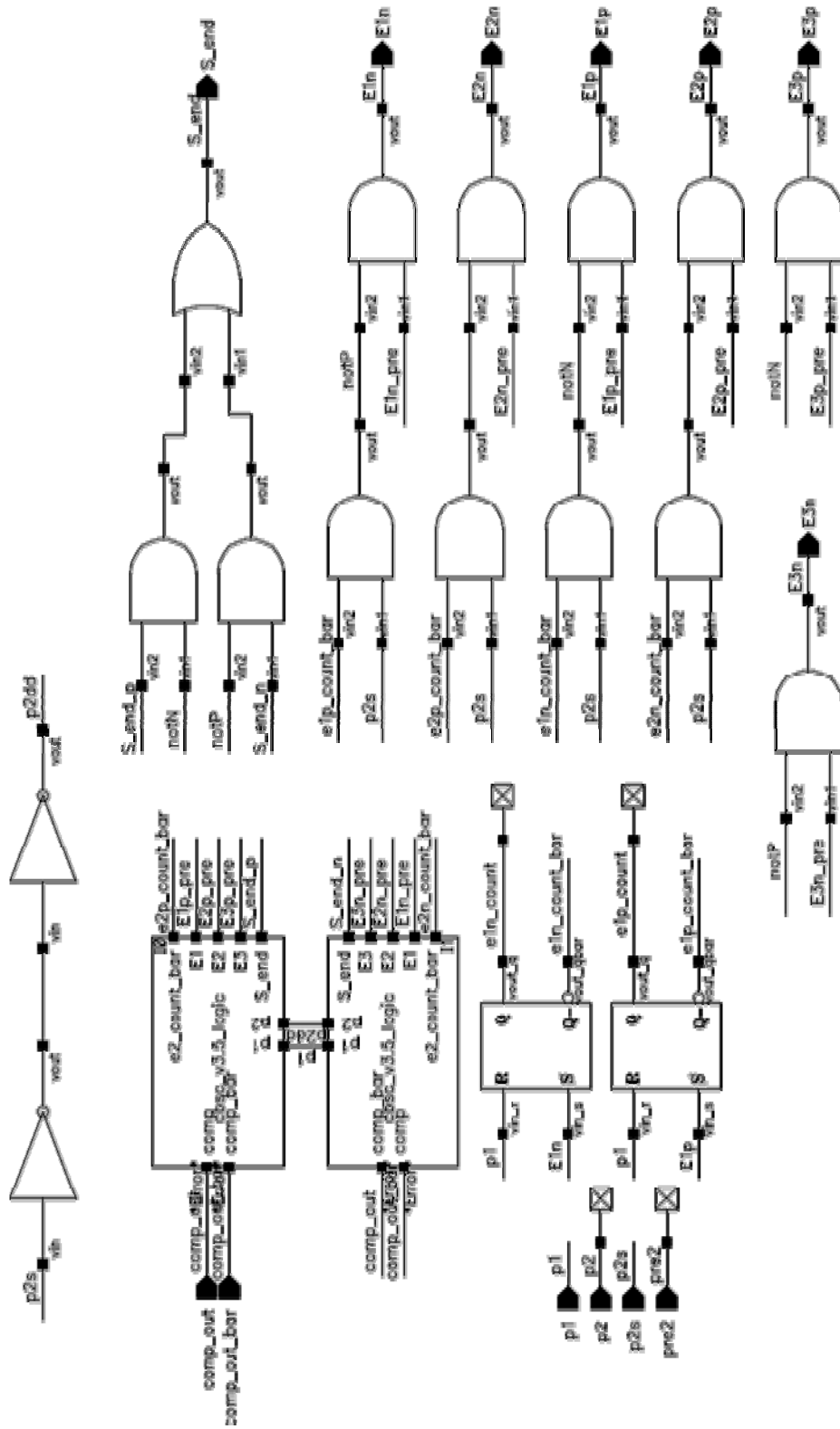
## B.8 UnitDAC



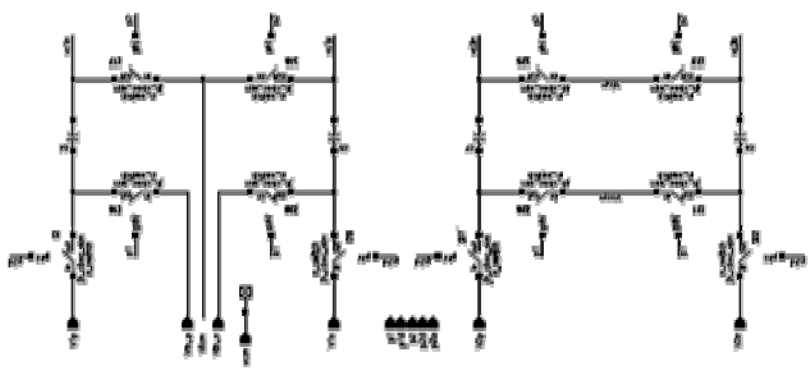
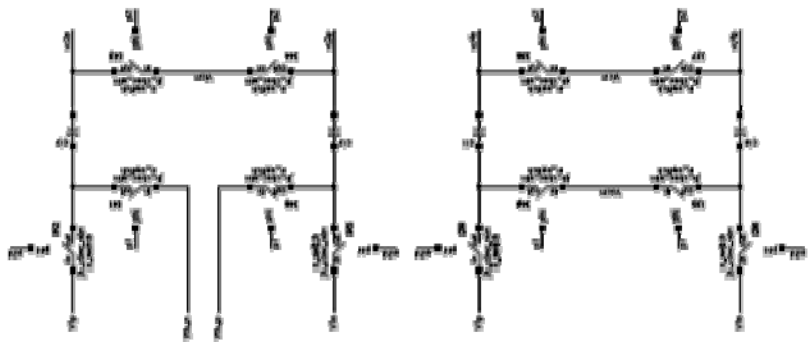
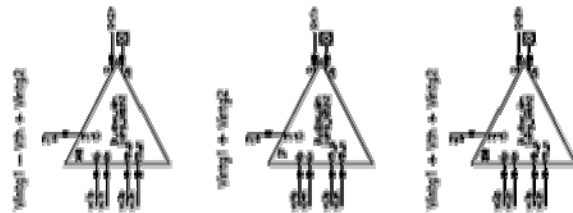
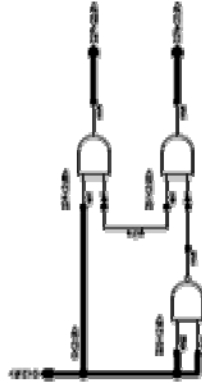
## B.9 CBSC with Dummy Branch



## B.10 Logic of CBSC with Dummy Branch



## B.11 *Qtzr* in CBSC

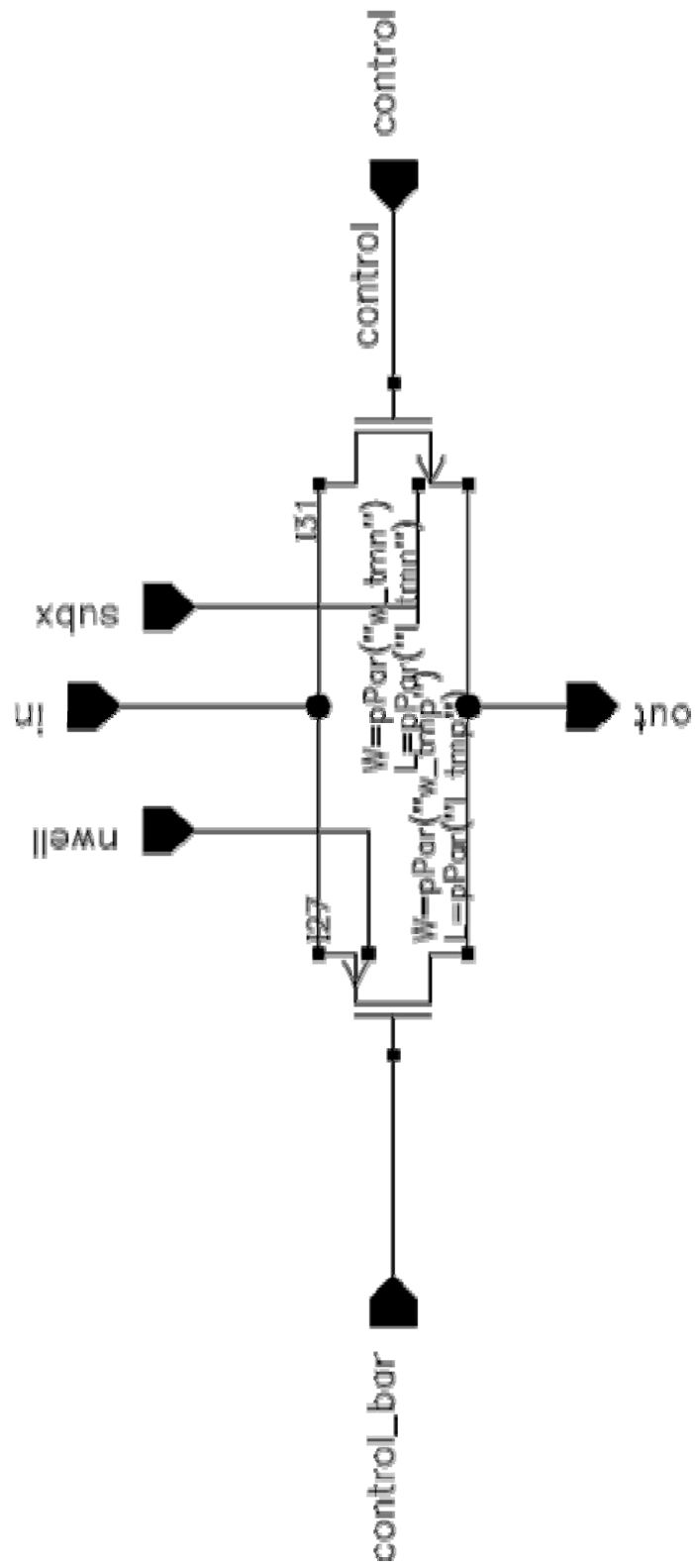


$$\frac{1}{s} \rightarrow \int$$

$$\frac{1}{s} \rightarrow \int$$

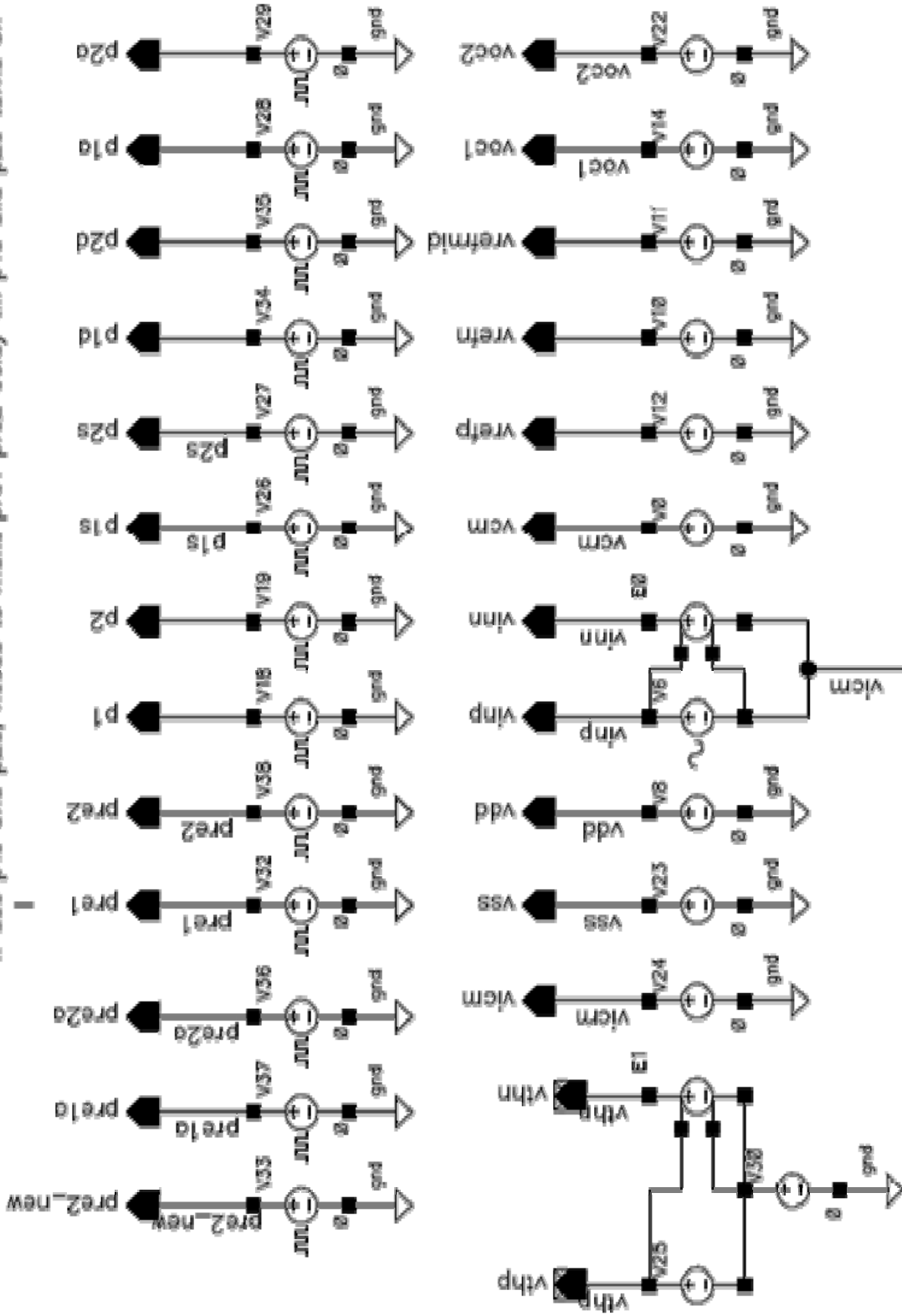


## B.12 Transmission Gate



## B.13 Reference Voltages in CBSC

if use p1d and p2d, needs to make pre1 pre2 delay till p1d and p2d turns on



## Reference

- [1] G. Torres, “How analog-to-digital converter (ADC) works,” [Online Document], Available HTTP: <http://www.hardwaresecrets.com/article/317>
- [2] Z. Moussaoui and G. Miller, “Digital power control highlights,” [Online Document], Available HTTP: <http://www.intersil.com/data/wp/WP0589.pdf>
- [3] R. Schreier and G. Temes, “Understanding delta-sigma data converters,” New Jersey: IEEE Press, 2005
- [4] T Sepke, J. K. Fiorenza, C. G. Sodini, P. Holloway, and H.-S. Lee, “Comparator based switched capacitor circuits for scaled CMOS technologies” in IEEE J. Solid-State Circuits, Vol. 41, no. 12, pp. 2658-2668, Dec. 2006.
- [5] M. Guyton and H.-S. Lee, “Low-voltage comparator-based switched-capacitor sigma-delta ADC” [Online Document], Available HTTP: [http://mtlweb.mit.edu/research/annual\\_reports/2006/pdf/cs/cs\\_29.pdf](http://mtlweb.mit.edu/research/annual_reports/2006/pdf/cs/cs_29.pdf)
- [6] T Sepke, J. K. Fiorenza, C. G. Sodini, P. Holloway, and H.-S. Lee, “Comparator based switched capacitor circuits for scaled CMOS technologies” in IEEE ISSCC Dig. Tech. Papers, Feb. 2006, pp. 220-221
- [7] Katanzag, “Delta-sigma modulation” [Online document], 2006, Available HTTP: [http://en.wikipedia.org/wiki/Flip-flop\\_\(electronics\)](http://en.wikipedia.org/wiki/Flip-flop_(electronics))
- [8] Mano, M. Morris; Kime, Charles R, *Logic and Computer Design Fundamentals, 3rd Edition*. Upper Saddle River, NJ, USA: Pearson Education International. pp. pg283. ISBN 0-13-1911651.
- [9] Todd C. Sepke, “Comparator Design and Analysis for Comparator-Based Switched-Capacitor Circuits”, 2006, MIT internal thesis collection
- [10] M. Momeni, D. Prelog, B. Horvat, M. Glesner, “Comparator-Based Switched-Capacitor, Delta-Sigma Modulation”, in Contemporary Engineering Sciences, Vol. 1, 2008, no. 1, 1 - 13